

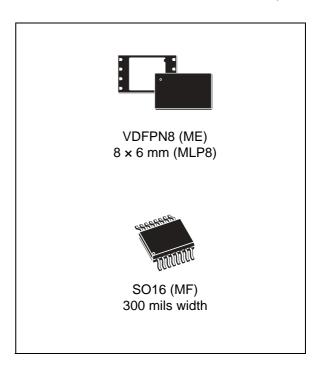
M25PX64

64-Mbit, dual I/O, 4-Kbyte subsector erase, serial flash memory with 75 MHz SPI bus interface

Preliminary Data

Features

- SPI bus compatible serial interface
- 75 MHz (maximum) clock frequency
- 2.7 V to 3.6 V single supply voltage
- Dual input/output instructions resulting in an equivalent clock frequency of 150 MHz:
 - Dual output fast read instruction
 - Dual input fast program instruction
- Whole memory continuously read by sending once a fast read or a dual output fast read instruction and an address
- 64 Mbit Flash memory
 - Uniform 4-Kbyte subsectors
 - Uniform 64-Kbyte sectors
- Additional 64-byte user-lockable, one-time programmable (OTP) area
- Erase capability
 - Subsector (4-Kbyte) granularity
 - Sector (64-Kbyte) granularity
 - Bulk erase (64 Mbits) in 35 s (typical with V_{PP} = 9 V)
- Write protections
 - Software write protection applicable to every 64-Kbyte sector (volatile lock bit)
 - Hardware write protection: protected area size defined by three non-volatile bits (BP0, BP1 and BP2)
- Deep power-down mode: 5 µA (typical)
- Electronic signature
 - JEDEC standard two-byte signature (7117h)
 - Unique ID code (UID) with 16 bytes readonly, available upon customer request
- More than 100 000 write cycles per sector
- More than 20 years data retention
- Packages
 - ECOPACK® (RoHS compliant)



Contents M25PX64

Contents

1	Desc	cription
2	Sign	al descriptions 9
	2.1	Serial data output (DQ1)
	2.2	Serial data input (DQ0)
	2.3	Serial Clock (C)
	2.4	Chip Select (S)
	2.5	Hold (HOLD)
	2.6	Write protect/enhanced program supply voltage (\overline{W}/V_{PP})
	2.7	V _{CC} supply voltage
	2.8	V _{SS} ground
3	SPI	modes11
4	Ope	rating features13
	4.1	Page programming
	4.2	Dual input fast program
	4.3	Subsector erase, sector erase and bulk erase
	4.4	Polling during a write, program or erase cycle
	4.5	Fast bulk erase mode
	4.6	Active power, standby power and deep power-down modes
	4.7	Status register
	4.8	Protection modes
		4.8.1 Protocol-related protections
		4.8.2 Specific hardware and software protection
	4.9	Hold condition
5	Mem	ory organization19
6	Instr	ructions
	6.1	Write enable (WREN)
	6.2	Write disable (WRDI)

	6.3	Read identification (RDID)
	6.4	Read status register (RDSR)
		6.4.1 WIP bit
		6.4.2 WEL bit
		6.4.3 BP2, BP1, BP0 bits
		6.4.4 Top/bottom bit
	0.5	6.4.5 SRWD bit
	6.5	Write status register (WRSR)
	6.6	Read data bytes (READ)
	6.7	Read data bytes at higher speed (FAST_READ)
	6.8	Dual output fast read (DOFR)
	6.9	Read lock register (RDLR)
	6.10	Read OTP (ROTP)
	6.11	Page program (PP)
	6.12	Dual input fast program (DIFP)43
	6.13	Program OTP instruction (POTP)
	6.14	Write to lock register (WRLR)
	6.15	Subsector erase (SSE)
	6.16	Sector erase (SE)
	6.17	Bulk erase (BE)
	6.18	Deep power-down (DP)51
	6.19	Release from deep power-down (RDP)52
7	Power	-up and power-down
8	Initial	delivery state
9	Maxin	um ratings
10	DC ar	d AC parameters56
11	Packa	ge mechanical
12	Order	ng information
13	Revis	on history65

List of tables M25PX64

List of tables

Table 1.	Signal names	7
Table 2.	Software protection truth table (sectors 0 to 127, 64-Kbyte granularity)	16
Table 3.	Protected area sizes	
Table 4.	Memory organization	20
Table 5.	Instruction set	27
Table 6.	Read identification (RDID) data-out sequence	30
Table 7.	Status register format	32
Table 8.	Protection modes	35
Table 9.	Lock register out	39
Table 10.	Lock register in	47
Table 11.	Power-up timing and VWI threshold	
Table 12.	Absolute maximum ratings	55
Table 13.	Operating conditions	56
Table 14.	AC measurement conditions	56
Table 15.	Capacitance	56
Table 16.	DC characteristics	57
Table 17.	AC characteristics	58
Table 18.	VDFPN8 (MLP8) 8-lead very thin dual flat package no lead,	
	8 x 6 mm, package mechanical data	62
Table 19.	SO16 wide - 16-lead plastic small outline, 300 mils body width, mechanical data	63
Table 20.	Ordering information scheme	64
Table 21.	Document revision history	65

M25PX64 List of figures

List of figures

Figure 1.	Logic diagram	7
Figure 2.	VDFPN8 connections	7
Figure 3.	SO16 connections	
Figure 4.	Bus master and memory devices on the SPI bus	. 11
Figure 5.	SPI modes supported	. 12
Figure 6.	Hold condition activation	. 18
Figure 7.	Block diagram	. 19
Figure 8.	Write enable (WREN) instruction sequence	. 28
Figure 9.	Write disable (WRDI) instruction sequence	
Figure 10.	Read identification (RDID) instruction sequence and data-out sequence	. 31
Figure 11.	Read status register (RDSR) instruction sequence and data-out sequence	. 33
Figure 12.	Write status register (WRSR) instruction sequence	. 34
Figure 13.	Read data bytes (READ) instruction sequence and data-out sequence	. 36
Figure 14.	Read data bytes at higher speed (FAST_READ) instruction sequence	
	and data-out sequence	. 37
Figure 15.	Dual output fast read instruction sequence	
Figure 16.	Read lock register (RDLR) instruction sequence and data-out sequence	. 39
Figure 17.	Read OTP (ROTP) instruction and data-out sequence	. 40
Figure 18.	Page program (PP) instruction sequence	. 42
Figure 19.	Dual input fast program (DIFP) instruction sequence	. 44
Figure 20.	Program OTP (POTP) instruction sequence	. 46
Figure 21.	How to permanently lock the 64 OTP bytes	. 46
Figure 22.	Write to lock register (WRLR) instruction sequence	. 47
Figure 23.	Subsector erase (SSE) instruction sequence	. 48
Figure 24.	Sector erase (SE) instruction sequence	. 49
Figure 25.	Bulk erase (BE) instruction sequence	. 50
Figure 26.	Deep power-down (DP) instruction sequence	. 51
Figure 27.	Release from deep power-down (RDP) instruction sequence	. 52
Figure 28.	Power-up timing	
Figure 29.	AC measurement I/O waveform	. 56
Figure 30.	Serial input timing	. 59
Figure 31.	Write protect setup and hold timing during WRSR when SRWD=1	. 60
Figure 32.	Hold timing	. 60
Figure 33.	Output timing	. 61
Figure 34.	V _{PPH} timing	. 61
Figure 35.	VDFPN8 (MLP8) 8-lead very thin dual flat package no lead,	
	8 x 6 mm, package outline	. 62
Figure 36.	SO16 wide - 16-lead plastic small outline, 300 mils body width, package outline	. 63

Description M25PX64

1 Description

The M25PX64 is a 64-Mbit (8 Mbits x 8) serial flash memory, with advanced write protection mechanisms, accessed by a high speed SPI-compatible bus.

The M25PX64 supports two new, high-performance dual input/output instructions:

- Dual output fast read (DOFR) instruction used to read data at up to 75 MHz by using both pin DQ1 and pin DQ0 as outputs
- Dual input fast program (DIFP) instruction used to program data at up to 75 MHz by using both pin DQ1 and pin DQ0 as inputs

These new instructions double the transfer bandwidth for read and program operations.

The memory can be programmed 1 to 256 bytes at a time, using the page program instruction.

The memory is organized as 128 sectors that are further divided into 16 subsectors each (2048 subsectors in total).

The memory can be erased a 4-Kbyte subsector at a time, a 64-Kbyte sector at a time, or as a whole. It can be write protected by software using a mix of volatile and non-volatile protection features, depending on the application needs. The protection granularity is of 64 Kbytes (sector granularity).

An enhanced fast bulk erase mode is available to speed up bulk erase operations in factory environment. The device enters this mode whenever the V_{PPH} voltage is applied to the write protect/enhanced program supply voltage pin (\overline{W}/V_{PP}) .

The M25PX64 has 64 one-time-programmable bytes (OTP bytes) that can be read and programmed using two dedicated instructions, Read OTP (ROTP) and Program OTP (POTP), respectively. These 64 bytes can be permanently locked by a particular program OTP (POTP) sequence. Once they have been locked, they become read-only and this state cannot be reverted.

Further features are available as additional security options. More information on these security features is available, upon completion of an NDA (nondisclosure agreement), and are, therefore, not described in this datasheet. For more details of this option contact your nearest Numonyx sales office.

M25PX64 Description

Figure 1. Logic diagram

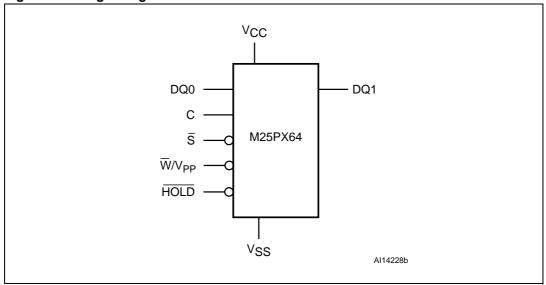
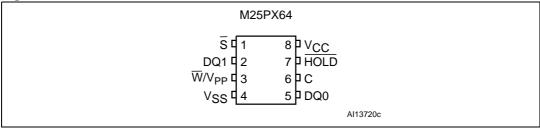


Table 1. Signal names

Signal name	Function	Direction
С	Serial Clock	Input
DQ0	Serial Data input	I/O ⁽¹⁾
DQ1	Serial Data output	I/O ⁽²⁾
S	Chip Select	Input
W/V _{PP}	Write Protect/Enhanced Program supply voltage	Input
HOLD	Hold	Input
V _{CC}	Supply voltage	_
V _{SS}	Ground	_

- 1. Serves as an output during dual output fast read (DOFR) instructions.
- 2. Serves as an input during dual input fast program (DIFP) instructions.

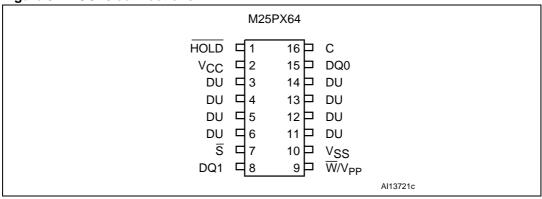
Figure 2. VDFPN8 connections



- There is an exposed central pad on the underside of the VDFPN8 package. This is pulled, internally, to V_{SS}, and must not be allowed to be connected to any other voltage or signal line on the PCB.
- 2. See Package mechanical section for package dimensions, and how to identify pin-1.

Description M25PX64

Figure 3. SO16 connections



- 1. DU = don't use.
- 2. See *Package mechanical* section for package dimensions, and how to identify pin-1.

M25PX64 Signal descriptions

2 Signal descriptions

2.1 Serial data output (DQ1)

This output signal is used to transfer data serially out of the device. Data are shifted out on the falling edge of Serial Clock (C).

During the dual input fast program (DIFP) instruction, pin DQ1 is used as an input. It is latched on the rising edge of the Serial Clock (C).

2.2 Serial data input (DQ0)

This input signal is used to transfer data serially into the device. It receives instructions, addresses, and the data to be programmed. Values are latched on the rising edge of Serial Clock (C).

During the dual output fast read (DOFR) instruction, pin DQ0 is used as an output. Data are shifted out on the falling edge of the Serial Clock (C).

2.3 Serial Clock (C)

This input signal provides the timing of the serial interface. Instructions, addresses, or data present at serial data input (DQ0) are latched on the rising edge of Serial Clock (C). Data on serial data output (DQ1) changes after the falling edge of Serial Clock (C).

2.4 Chip Select (\overline{S})

When this input signal is High, the device is deselected and serial data output (DQ1) is at high impedance. Unless an internal program, erase or write status register cycle is in progress, the device will be in the standby power mode (this is not the deep power-down mode). Driving Chip Select (\overline{S}) Low enables the device, placing it in the active power mode.

After power-up, a falling edge on Chip Select (\overline{S}) is required prior to the start of any instruction.

2.5 Hold (HOLD)

The Hold (HOLD) signal is used to pause any serial communications with the device without deselecting the device.

During the hold condition, the serial data output (DQ1) is high impedance, and serial data input (DQ0) and Serial Clock (C) are don't care.

To start the hold condition, the device must be selected, with Chip Select (\overline{S}) driven Low.

Signal descriptions M25PX64

2.6 Write protect/enhanced program supply voltage (\overline{W}/V_{PP})

 \overline{W}/V_{PP} is both a control input and a power supply pin. The two functions are selected by the voltage range applied to the pin.

If the \overline{W}/V_{PP} input is kept in a low voltage range (0 V to V_{CC}) the pin is seen as a control input. This input signal is used to freeze the size of the area of memory that is protected against program or erase instructions (as specified by the values in the BP2, BP1 and BP0 bits of the status register. See *Table 9*).

If V_{PP} is in the range of V_{PPH} (as defined in *Table 14*) it acts as an additional power supply during the bulk erase cycle. In this case V_{PP} must be stable until the bulk erase algorithm is completed.

2.7 V_{CC} supply voltage

V_{CC} is the supply voltage.

2.8 V_{SS} ground

V_{SS} is the reference for the V_{CC} supply voltage.

M25PX64 SPI modes

3 SPI modes

These devices can be driven by a microcontroller with its SPI peripheral running in either of the two following modes:

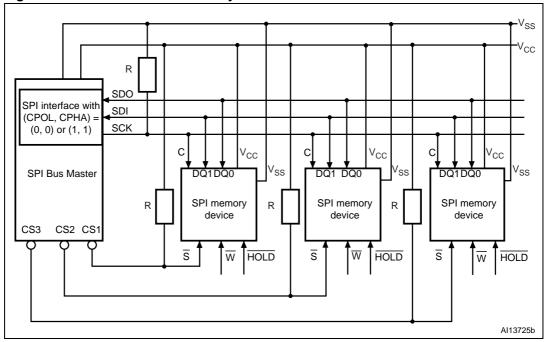
- CPOL=0, CPHA=0
- CPOL=1, CPHA=1

For these two modes, input data is latched in on the rising edge of Serial Clock (C), and output data is available from the falling edge of Serial Clock (C).

The difference between the two modes, as shown in *Figure 5*, is the clock polarity when the bus master is in standby mode and not transferring data:

- C remains at 0 for (CPOL=0, CPHA=0)
- C remains at 1 for (CPOL=1, CPHA=1)

Figure 4. Bus master and memory devices on the SPI bus

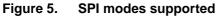


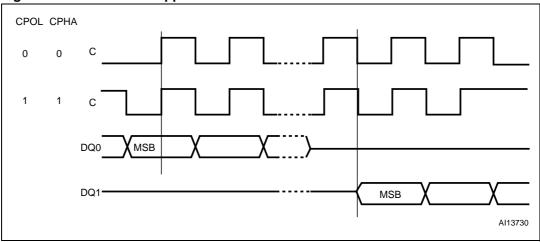
1. The Write Protect $\overline{(W)}$ and Hold $\overline{(HOLD)}$ signals should be driven, High or Low as appropriate.

Figure 4 shows an example of three devices connected to an MCU, on an SPI bus. Only one device is selected at a time, so only one device drives the serial data output (DQ1) line at a time, the other devices are high impedance. Resistors R (represented in Figure 4) ensure that the M25PX64 is not selected if the bus master leaves the \overline{S} line in the high impedance state. As the bus master may enter a state where all inputs/outputs are in high impedance at the same time (for example, when the bus master is reset), the clock line (C) must be connected to an external pull-down resistor so that, when all inputs/outputs become high impedance, the \overline{S} line is pulled High while the C line is pulled Low (thus ensuring that \overline{S} and C do not become High at the same time, and so, that the t_{SHCH} requirement is met). The typical value of R is 100 kΩ, assuming that the time constant R*C_p (C_p = parasitic capacitance of the bus line) is shorter than the time during which the bus master leaves the SPI bus in high impedance.

SPI modes M25PX64

Example: $C_p = 50$ pF, that is $R^*C_p = 5$ $\mu s \ll 5$ the application must ensure that the bus master never leaves the SPI bus in the high impedance state for a time period shorter than 5 μs .





M25PX64 Operating features

4 Operating features

4.1 Page programming

To program one data byte, two instructions are required: write enable (WREN), which is one byte, and a page program (PP) sequence, which consists of four bytes plus data. This is followed by the internal program cycle (of duration tpp).

To spread this overhead, the page program (PP) instruction allows up to 256 bytes to be programmed at a time (changing bits from '1' to '0'), provided that they lie in consecutive addresses on the same page of memory.

For optimized timings, it is recommended to use the page program (PP) instruction to program all consecutive targeted bytes in a single sequence versus using several page program (PP) sequences with each containing only a few bytes (see *Page program (PP)* and *Table 17: AC characteristics*).

4.2 Dual input fast program

The dual input fast program (DIFP) instruction makes it possible to program up to 256 bytes using two input pins at the same time (by changing bits from '1' to '0').

For optimized timings, it is recommended to use the dual input fast program (DIFP) instruction to program all consecutive targeted bytes in a single sequence rather to using several dual input fast program (DIFP) sequences each containing only a few bytes (see Section 6.12: Dual input fast program (DIFP)).

4.3 Subsector erase, sector erase and bulk erase

The page program (PP) instruction allows bits to be reset from '1' to '0'. Before this can be applied, the bytes of memory need to have been erased to all 1s (FFh). This can be achieved either a subsector at a time, using the subsector erase (SSE) instruction, a sector at a time, using the sector erase (SE) instruction, or throughout the entire memory, using the bulk erase (BE) instruction. This starts an internal erase cycle (of duration t_{SSE}, t_{SE} or t_{BE}).

The erase instruction must be preceded by a write enable (WREN) instruction.

4.4 Polling during a write, program or erase cycle

A further improvement in the time to write status register (WRSR), program OTP (POTP), program (PP), dual input fast program (DIFP) or erase (SSE, SE or BE) can be achieved by not waiting for the worst case delay (t_W , t_{PP} , t_{SSE} , t_{SE} , or t_{BE}). The write in progress (WIP) bit is provided in the status register so that the application program can monitor its value, polling it to establish when the previous write cycle, program cycle or erase cycle is complete.

Operating features M25PX64

4.5 Fast bulk erase mode

The fast bulk erase mode is used to speed up bulk erase operations. The device enters the fast bulk erase mode during a bulk erase instruction whenever a voltage equal to V_{PPH} is applied to the \overline{W}/V_{PP} pin.

The use of the fast bulk erase mode requires specific operating conditions in addition to the normal ones (V_{CC} must be within the normal operating range):

- the voltage applied to the \overline{W}/V_{PP} pin must be equal to V_{PPH} (see *Table 13*)
- ambient temperature, T_A must be 25 °C ±10 °C,
- the cumulated time during which \overline{W}/V_{PP} is at V_{PPH} should be less than 80 hours.

4.6 Active power, standby power and deep power-down modes

When Chip Select (\overline{S}) is Low, the device is selected, and in the active power mode.

When Chip Select (\overline{S}) is High, the device is deselected, but could remain in the active power mode until all internal cycles have completed (program, erase, write status register). The device then goes in to the standby power mode. The device consumption drops to I_{CC1} .

The deep power-down mode is entered when the specific instruction (the deep power-down (DP) instruction) is executed. The device consumption drops further to I_{CC2} . The device remains in this mode until another specific instruction (the release from deep power-down (RDP) instruction) is executed.

While in the deep power-down mode, the device ignores all write, program and erase instructions (see *Section 6.18: Deep power-down (DP)*), this can be used as an extra software protection mechanism, when the device is not in active use, to protect the device from inadvertent write, program or erase instructions.

4.7 Status register

The status register contains a number of status and control bits that can be read or set (as appropriate) by specific instructions. See *Section 6.4: Read status register (RDSR)* for a detailed description of the status register bits.

M25PX64 Operating features

4.8 Protection modes

There are protocol-related and specific hardware and software protection modes. They are described below.

4.8.1 Protocol-related protections

The environments where non-volatile memory devices are used can be very noisy. No SPI device can operate correctly in the presence of excessive noise. To help combat this, the M25PX64 features the following data protection mechanisms:

- Power on reset and an internal timer (t_{PUW}) can provide protection against inadvertent changes while the power supply is outside the operating specification
- Program, erase and write status register instructions are checked that they consist of a number of clock pulses that is a multiple of eight, before they are accepted for execution
- All instructions that modify data must be preceded by a write enable (WREN)
 instruction to set the write enable latch (WEL) bit. This bit is returned to its reset state
 by the following events:
 - Power-up
 - Write disable (WRDI) instruction completion
 - Write status register (WRSR) instruction completion
 - Write to lock register (WRLR) instruction completion
 - Program OTP (POTP) instruction completion
 - Page program (PP) instruction completion
 - Dual input fast program (DIFP) instruction completion
 - Subsector erase (SSE) instruction completion
 - Sector erase (SE) instruction completion
 - Bulk erase (BE) instruction completion
- In addition to the low power consumption feature, the deep power-down mode offers extra software protection, as all write, program and erase instructions are ignored.

√ numonyx 15/66

Operating features M25PX64

4.8.2 Specific hardware and software protection

There are two software protected modes, SPM1 and SPM2, that can be combined to protect the memory array as required. The SPM2 can be locked by hardware with the help of the \overline{W} input pin.

SPM1 and SPM2

 The first software protected mode (SPM1) is managed by specific lock registers assigned to each 64-Kbyte sector.

The lock registers can be read and written using the read lock register (RDLR) and write to lock register (WRLR) instructions.

In each lock register two bits control the protection of each sector: the write lock bit and the lock down bit.

Write lock bit:

The write lock bit determines whether the contents of the sector can be modified (using the write, program or erase instructions). When the write lock bit is set to '1', the sector is write protected – any operations that attempt to change the data in the sector will fail. When the write lock bit is reset to '0', the sector is not write protected by the lock register, and may be modified.

Lock down bit:

The lock down bit provides a mechanism for protecting software data from simple hacking and malicious attack. When the lock down bit is set to '1', further modification to the write lock and lock down bits cannot be performed. A power-up is required before changes to these bits can be made. When the lock down bit is reset to '0', the write lock and lock down bits can be changed.

The definition of the lock register bits is given in Table 9: Lock register out.

Table 2. Software protection truth table (sectors 0 to 127, 64-Kbyte granularity)

Sector lock	c register		
Lock down bit	Write lock bit	Protection status	
O Sector unprotected from program/erase/write operations, protection started reversible		Sector unprotected from program/erase/write operations, protection status reversible	
O Sector protected from program/erase/write operations, protection reversible		Sector protected from program/erase/write operations, protection status reversible	
1 1 1 1		Sector unprotected from program/erase/write operations, Sector protection status cannot be changed except by a power-up.	
1 1		Sector protected from program/erase/write operations, Sector protection status cannot be changed except by a power-up.	

• the second software protected mode (SPM2) uses the block protect bits (see Section 6.4.3: BP2, BP1, BP0 bits) and the top/bottom bit (see Section 6.4.4: Top/bottom bit) to allow part of the memory to be configured as read-only.

M25PX64 Operating features

Table 3. Protected area sizes

Status register contents			er	Memory content		
TB bit	BP bit 2	BP bit 1	BP bit 0	Protected area	Unprotected area	
0	0	0	0	none	All sectors ⁽¹⁾ (128 sectors: 0 to 127)	
0	0	0	1	Upper 64th (2 sectors: 126 and 127)	Lower 63/64ths (126 sectors: 0 to 125)	
0	0	1	0	Upper 32nd (4 sectors: 124 to 127)	Lower 31/32nds (124 sectors: 0 to 123)	
0	0	1	1	Upper 16th (8 sectors: 120 to 127)	Lower 15/16ths (120 sectors: 0 to 119)	
0	1	0	0	Upper 8th (16 sectors: 56 to 63)	Lower 7/8ths (112 sectors: 0 to 111)	
0	1	0	1	Upper quarter (32 sectors: 96 to 127)	Lower three-quarters (96 sectors: 0 to 95)	
0	1	1	0	Upper half (64 sectors: 64 to 127)	Lower half (64 sectors: 0 to 63)	
0	1	1	1	All sectors (128 sectors: 0 to 127)	none	
1	0	0	0	none	All sectors ⁽¹⁾ (128 sectors: 0 to 128)	
1	0	0	1	Lower 64th (2 sectors: 0 to1)	Upper 63/64ths (126 sectors: 2 to 127)	
1	0	1	0	Lower 32nd (4 sectors: 0 to 3)	Upper 31/32nds (124 sectors: 4 to 127)	
1	0	1	1	Lower 16th (8 sectors: 0 to 7)	Upper 15/16ths (120 sectors: 8 to 127)	
1	1	0	0	Lower 8th (16 sectors: 0 to15)	Upper 7/8ths (112 sectors: 16 to 127)	
1	1	0	1	Lower 4th (32 sectors: 0 to 31)	Upper 3/4ths (96 sectors: 32 to 127)	
1	1	1	0	Lower half (64 sectors: 0 to 63)	Upper half (64 sectors: 64 to 127)	
1	1	1	1	All sectors (128 sectors: 0 to 127) none		

^{1.} The device is ready to accept a bulk erase instruction if, and only if, all block protect (BP2, BP1, BP0) are 0.

As a second level of protection, the Write Protect signal (applied on the \overline{W}/V_{PP} pin) can freeze the status register in a read-only mode. In this mode, the block protect bits (BP2, BP1, BP0) and the status register write disable bit (SRWD) are protected. For more details, see Section 6.5: Write status register (WRSR).

Numonyx 17/66

Operating features M25PX64

4.9 Hold condition

The Hold (HOLD) signal is used to pause any serial communications with the device without resetting the clocking sequence. However, taking this signal Low does not terminate any write status register, program or erase cycle that is currently in progress.

To enter the hold condition, the device must be selected, with Chip Select (\overline{S}) Low.

The hold condition starts on the falling edge of the Hold (HOLD) signal, provided that this coincides with Serial Clock (C) being Low (as shown in *Figure 6*).

The hold condition ends on the rising edge of the Hold (HOLD) signal, provided that this coincides with Serial Clock (C) being Low.

If the falling edge does not coincide with Serial Clock (C) being Low, the hold condition starts after Serial Clock (C) next goes Low. Similarly, if the rising edge does not coincide with Serial Clock (C) being Low, the hold condition ends after Serial Clock (C) next goes Low (this is shown in *Figure 6*).

During the hold condition, the serial data output (DQ1) is high impedance, and serial data input (DQ0) and Serial Clock (C) are don't care.

Normally, the device is kept selected, with Chip Select (\overline{S}) driven Low, for the whole duration of the hold condition. This is to ensure that the state of the internal logic remains unchanged from the moment of entering the hold condition.

If Chip Select (S) goes High while the device is in the Hold condition, this has the effect of resetting the internal logic of the device. To restart communication with the device, it is necessary to drive Hold $(\overline{\text{HOLD}})$ High, and then to drive Chip Select $(\overline{\textbf{S}})$ Low. This prevents the device from going back to the hold condition.

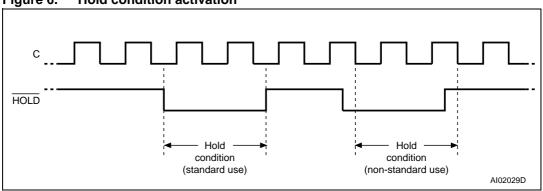


Figure 6. Hold condition activation

18/66 **№** numonyx

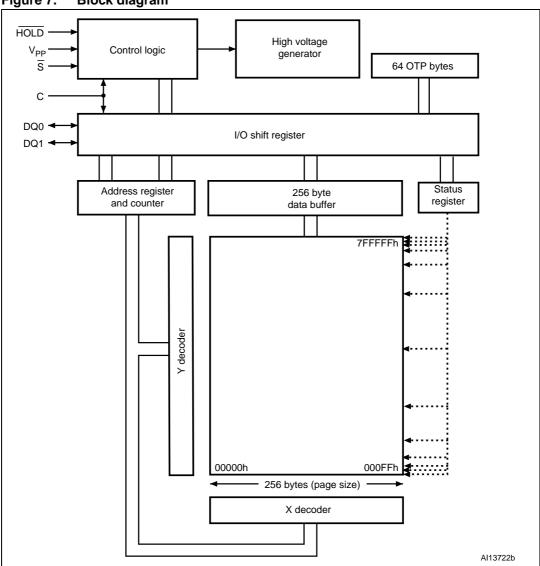
5 Memory organization

The memory is organized as:

- 8 388 608 bytes (8 bits each)
- 2048 subsectors (4 Kbytes each)
- 128 sectors (64 Kbytes each)
- 32768 pages (256 bytes each)
- 64 OTP bytes located outside the main memory array.

Each page can be individually programmed (bits are programmed from '1' to '0'). The device is subsector, sector or bulk erasable (bits are erased from '0' to '1') but not page erasable.

Figure 7. Block diagram



Memory organization M25PX64

Table 4. Memory organization

Sector	Subsector	Address range	
	2047	7FF000h	7FFFFFh
127	:	:	i
	2032	7F0000h	7F0FFFh
	2031	7EF000h	7EFFFFh
126	i	:	i
	2016	7E0000h	7E0FFFh
	2015	7DF000h	7DFFFFh
125	i	i	i
	2000	7D0000h	7D0FFFh
	1999	7CF000h	7CFFFFh
124	i	i	i
	1984	7C0000h	7C0FFFh
	1983	7BF000h	7BFFFFh
123	:	:	i
	1968	7B0000h	7B0FFFh
	1967	7AF000h	7AFFFFh
122	ŧ	:	i
	1952	7A0000h	7A0FFFh
	1951	79F000h	79FFFFh
121	:	:	:
	1936	790000h	790FFFh
	1935	78F000h	78FFFFh
120	:	:	:
	1920	780000h	780FFFh
	1919	77F000h	77FFFFh
119	÷	:	i
	1904	770000h	770FFFh
	1903	76F000h	76FFFFh
118	:	:	:
	1888	760000h	760FFFh
	1887	75F000h	75FFFFh
117	i	i	i
	1872	750000h	750FFFh

Sector	Subsector	Addres	s range
	1871	74F000h	74FFFFh
116	:	:	:
	1856	740000h	740FFFh
	1855	73F000h	73FFFFh
115	÷	÷	i
	1840	730000h	730FFFh
	1839	72F000h	72FFFFh
114	:	i	i
	1824	720000h	720FFFh
	1823	71F000h	71FFFFh
113	:	i	:
	1808	710000h	710FFFh
	1807	70F000h	70FFFFh
112	i	i	:
	1792	700000h	700FFFh
	1791	6FF000h	6FFFFFh
111	:	:	:
	1776	6F0000h	6F0FFFh
	1775	6EF000h	6EFFFFh
110			
	1760	6E0000h	6E0FFFh
	1759	6DF000h	6DFFFFh
109	:		
	1744	6D0000h	6D0FFFh
	1743	6CF000h	6CFFFFh
108	:		
	1728	6C0000h	6C0FFFh
	1727	6BF000h	6BFFFFh
107	:	:	:
	1712	6B0000h	6B0FFFh
	1711	6AF000h	6AFFFFh
106	:	:	:
	1696	6A0000h	6A0FFFh

M25PX64

Table 4. Memory organization (continued)

Sector	Subsector	Address range	
	1695	69F000h	69FFFFh
105	ŧ	:	i.
	1680	690000h	690FFFh
	1679	68F000h	68FFFFh
104	ŧ	:	i.
	1664	680000h	680FFFh
	1663	67F000h	67FFFh
103	÷	:	i.
	1648	670000h	670FFFh
	1647	66F000h	66FFFFh
102	÷	:	÷
	1632	660000h	660FFFh
	1631	65F000h	65FFFFh
101	:	:	÷
	1616	650000h	650FFFh
	1615	64F000h	64FFFFh
100	÷	i	÷
	1600	640000h	640FFFh
	1599	63F000h	63FFFFh
99	i	:	÷
	1584	630000h	630FFFh
	1583	62F000h	62FFFFh
98	i	:	÷
	1568	620000h	620FFFh
	1567	61F000h	61FFFFh
97	i	i	i
	1552	610000h	610FFFh
	1551	60F000h	60FFFFh
96	i	i	ŧ
	1536	600000h	600FFFh
	1535	5FF000h	5FFFFFh
95	i	i	ŧ
	1520	5F0000h	5F0FFFh

Sector	Subsector	Addres	s range
	1519	5EF000h	5EFFFFh
94	i.	÷	:
	1504	5E0000h	5E0FFFh
	1503	5DF000h	5DFFFFh
93	ŧ	ŧ	:
	464	5D0000h	5D0FFFh
	1487	5CF000h	5CFFFFh
92	:	:	:
	1472	5C0000h	5C0FFFh
	1471	5BF000h	5BFFFFh
91	:	:	:
	1456	5B0000h	5B0FFFh
	1455	5AF000h	5AFFFFh
90	:	:	:
	1440	5A0000h	5A0FFFh
	1439	59F000h	59FFFFh
89	:	i	:
	1424	590000h	590FFFh
	1423	58F000h	58FFFFh
88	:	:	:
	1408	580000h	580FFFh
	1407	57F000h	57FFFFh
87	:		:
	1392	570000h	570FFFh
	1391	56F000h	56FFFFh
86	:	•••	:
	1376	560000h	560FFFh
	1375	55F000h	55FFFFh
85	:	:	:
	1360	550000h	550FFFh
	1359	54F000h	54FFFFh
84	:	:	:
	1344	540000h	540FFFh

Memory organization M25PX64

Table 4. Memory organization (continued)

Sector	Subsector	Address range	
	1343	53F000h	53FFFFh
83	:	:	:
	1328	530000h	530FFFh
	1327	52F000h	52FFFFh
82	:	:	:
	1312	520000h	520FFFh
	1311	51F000h	51FFFFh
81	:	:	:
	1296	510000h	510FFFh
	1295	50F000h	50FFFFh
80	:	:	:
	1280	500000h	500FFFh
	1279	4FF000h	4FFFFFh
79	:	:	:
	1264	4F0000h	4F0FFFh
	1263	4EF000h	4EFFFFh
78	:	:	:
	1248	4E0000h	4E0FFFh
	1247	4DF000h	4DFFFFh
77	:	:	:
	1232	4D0000h	4D0FFFh
	1231	4CF000h	4CFFFFh
76	:	:	:
	1216	4C0000h	4C0FFFh
	1215	4BF000h	4BFFFFh
75	:	:	:
	1200	4B0000h	4B0FFFh
	1199	4AF000h	4AFFFFh
74			
	1184	4A0000h	4A0FFFh
	1183	49F000h	49FFFFh
73	:	:	i
	1168	490000h	490FFFh

Sector	Subsector	Address range		
	1167	48F000h	48FFFFh	
72	:	:	:	
	1152	480000h	480FFFh	
	1151	47F000h	47FFFFh	
71	:	:	:	
	1136	470000h	470FFFh	
	1135	46F000h	46FFFFh	
70	:	:	:	
	1120	460000h	460FFFh	
	1119	45F000h	45FFFFh	
69	:	:	:	
	1104	450000h	450FFFh	
	1103	44F000h	44FFFFh	
68	:	:	:	
	1088	440000h	440FFFh	
	1087	43F000h	43FFFFh	
67	:		:	
	1072	430000h	430FFFh	
	1071	42F000h	42FFFFh	
66	:		:	
	1056	420000h	420FFFh	
	1055	41F000h	41FFFFh	
65	:		:	
	1040	410000h	410FFFh	
	1039	40F000h	40FFFFh	
64	÷	:	:	
	1024	400000h	400FFFh	
	1023	3FF000h	3FF000h	
63	:	:	i	
	1008	3F0000h	3F0FFFh	
	1007	3EF000h	3EFFFFh	
62	÷	÷	i	
	992	3E0000h	3E0FFFh	

M25PX64

Table 4. Memory organization (continued)

Sector	Subsector	Addres	s range
	991	3DF000h	3DFFFFh
61	:	:	:
	976	3D0000h	3D0FFFh
	975	3CF000h	3CFFFFh
60	:	:	:
	960	3C0000h	3C0FFFh
	959	3BF000h	3BFFFFh
59	:	:	:
	944	3B0000h	3B0FFFh
	943	3AF000g	3AFFFFh
58	÷	:	:
	928	3A0000h	3A0FFFh
	927	39F000h	39FFFFh
57	÷	:	:
	912	390000h	390FFFh
	911	38F000h	38FFFFh
56	i	:	i
	896	380000h	380FFFh
	895	37F000h	37FFFFh
55	i	:	i
	880	370000h	370FFFh
	879	36F000h	36FFFFh
54	:	:	i
	864	360000h	360FFFh
	863	35F000h	35FFFFh
53	:	:	i
	848	350000h	350FFFh
	847	34F000h	34FFFFh
52	i	:	i
	832	340000h	340FFFh
	831	33F000h	33FFFFh
51	:	:	:
	816	330000h	330FFFh

Sector	Subsector	Addres	s range	
	815	32F000h	32FFFFh	
50	÷	÷	÷	
	800	320000h	320FFFh	
	799	31F000h	31FFFFh	
49	i	:	÷	
	784	310000h	310FFFh	
	783	30F000h	30FFFFh	
48	ŧ	ŧ	i	
	768	300000h	: 310FFFh 30FFFFh	
	767	2FF000h	2FFFFFh	
47	:	:	:	
	752	2F0000h	2F0FFFh	
	751	2EF000h	2EFFFFh	
46	:	:	:	
	736	2E0000h	2E0FFFh	
	735	2DF000h	2DFFFFh	
45	:	i	i	
	720	2D0000h	2D0FFFh	
	719	2CF000h	2CFFFFh	
44	:	i	i	
	704	2C0000h	2C0FFFh	
	703	2BF000h	2BFFFFh	
43	:	i	i	
	688	2B0000h	2B0FFFh	
	687	2AF000h	2AFFFFh	
42	815 32F000h 800 320000h 799 31F000h 784 310000h 768 300000h 752 2F0000h 736 2EF000h 736 2E0000h 720 2D0000h 704 2C0000h 703 2BF000h 688 2B0000h	÷		
	672	32F000h :: 320000h 31F000h :: 310000h 30F000h :: 300000h 2FF000h :: 2E0000h 2EF000h :: 2D0000h 2DF000h :: 2D0000h 2DF000h :: 2D0000h :: 2A0000h 2AF000h :: 2A0000h 29F000h :: 290000h ::	2A0FFFh	
	671	29F000h	29FFFFh	
41	800 320000h 799 31F000h 784 310000h 783 30F000h 768 300000h 767 2FF000h 47 :: 752 2F0000h 751 2EF000h 45 :: 720 2DF000h 44 :: 704 2CF000h 43 :: 688 2B0000h 42 :: 672 2AF000h 41 :: 656 290000h 655 28F000h	i		
	656	: 320000h 31F000h : 310000h : 30F000h : 2F0000h : 2CF000h : 2CF0000h : 2CF00000h	290FFFh	
	655	31F000h : 310000h 30F000h : 300000h 2FF000h : 2F0000h 2EF000h : 2D0000h 2CF000h : 2CF000h 2BF000h : 2B0000h 2AF000h : 2A0000h 29F000h : 299000h 28F000h : 299000h	28FFFFh	
40	<u> </u>	:	:	
	640	280000h	280FFFh	

Memory organization M25PX64

Table 4. Memory organization (continued)

Sector	Subsector	Addres	s range
	639	27F000h	27FFFFh
39	:	:	:
	624	270000h	270FFFh
	623	26F000h	26FFFFh
38	:	:	:
	608	260000h	260FFFh
	607	25F000h	25FFFFh
37	:	:	:
	592	250000h	250FFFh
	591	24F000h	24FFFFh
36	:	:	:
	576	240000h	240FFFh
	575	23F000h	23FFFFh
35	:	:	:
	560	230000h	230FFFh
	559	22F000h	22FFFFh
34	:	:	i
	544	220000h	220FFFh
	543	21F000h	21FFFFh
33	:	:	i
	528	210000h	210FFFh
	527	20F000h	20FFFFh
32	:	:	i
	512	200000h	200FFFh
	511	1FF000h	1FFFFFh
31	:	:	:
	496	1F0000h	1F0FFFh
	495	1EF000h	1EFFFFh
30	:	:	:
	480	260000h 25F000h :: 250000h 24F000h :: 240000h 23F000h :: 230000h 22F000h :: 220000h 21F000h :: 210000h :: 200000h 1FF000h :: 1F0000h :: 1F0000h	1E0FFFh
	479	1DF000h	1DFFFFh
29	:	:	i
	464	1D0000h	1D0FFFh

Sector	Subsector	Address range		
	463	1CF000h	1CFFFFh	
28	:	:	:	
	448	1C0000h	1C0FFFh	
	447	1BF000h	1BFFFFh	
27	:	:	:	
	432	1B0000h	1B0FFFh	
	431	1AF000h	1AFFFFh	
26	:	:	:	
	416	1A0000h	1A0FFFh	
	415	19F000h	19FFFFh	
25	:	:	:	
	400	190000h	190FFFh	
	399	18F000h	18FFFFh	
24	:	:	:	
	384	180000h	180FFFh	
	383	17F000h	17FFFFh	
23	:	i	:	
	368	170000h	170FFFh	
	367	16F000h	16FFFFh	
22	:		:	
	352	160000h	160FFFh	
	351	15F000h	15FFFFh	
21	:		:	
	336	150000h	150FFFh	
	335	14F000h	14FFFFh	
20	:	:	:	
	320	140000h	140FFFh	
	319	13F000h	13FFFFh	
19	i	i	:	
	304	130000h	130FFFh	
	303	12F000h	12FFFFh	
18	:	:	:	
	288	120000h	120FFFh	

Table 4. Memory organization (continued)

Sector	Subsector	Addres	s range
	287	11F000h	11FFFFh
17	:	:	i.
	272	110000h	110FFFh
	271	10F000h	10FFFFh
16	:	:	i.
	256	100000h	100FFFh
	255	FF000h	FFFFFh
15	:	:	i.
	240	F0000h	F0FFFh
	239	EF000h	EFFFFh
14	:	:	i.
	224	E0000h	E0FFFh
	223	DF000h	DFFFFh
13	:	:	:
	208	D0000h	D0FFFh
	207	CF000h	CFFFFh
12	:	:	i
	192	C0000h	C0FFFh
	191	BF000h	BFFFFh
11	i	:	i
	176	B0000h	B0FFFh
	175	AF000h	AFFFFh
10			
	160	A0000h	A0FFFh
	159	9F000h	9FFFFh
9	:	:	i
	144	90000h	90FFFh
	143	8F000h	8FFFFh
8	:	:	i
	128	80000h	80FFFh

Sector	Subsector	Address range		
	127	7F000h	7FFFFh	
7	:	:	:	
	112	70000h	70FFFh	
	111	6F000h	6FFFFh	
6	:	:	:	
	96	60000h	60FFFh	
	95	5F000h	5FFFFh	
5		:	:	
	80	50000h	50FFFh	
	79	4F000h	4FFFFh	
4		:	:	
	64	40000h	40FFFh	
	63	3F000h	3FFFFh	
3	:	:	:	
	48	30000h	30FFFh	
	47	2F000h	2FFFFh	
2	i	i	÷	
	32	20000h	20FFFh	
	31	1F000h	1FFFFh	
1	:	:	÷	
	16	10000h	10FFFh	
	15	0F000h	0FFFFh	
	i	i	÷	
	4	04000h	04FFFh	
0	3	03000h	03FFFh	
	2	02000h	02FFFh	
	1	01000h	01FFFh	
	0	00000h	00FFFh	

Instructions M25PX64

6 Instructions

All instructions, addresses and data are shifted in and out of the device, most significant bit first.

Serial data input(s) DQ0 (DQ1) is (are) sampled on the first rising edge of Serial Clock (C) after Chip Select $\overline{(S)}$ is driven Low. Then, the one-byte instruction code must be shifted in to the device, most significant bit first, on serial data input(s) DQ0 (DQ1), each bit being latched on the rising edges of Serial Clock (C).

The instruction set is listed in Table 5.

Every instruction sequence starts with a one-byte instruction code. Depending on the instruction, this might be followed by address bytes, or by data bytes, or by both or none.

In the case of a read data bytes (READ), read data bytes at higher speed (FAST_READ), dual output fast read (DOFR), read OTP (ROTP), read lock registers (RDLR), read status register (RDSR), read identification (RDID) or release from deep power-down (RDP) instruction, the shifted-in instruction sequence is followed by a data-out sequence. Chip Select (\overline{S}) can be driven High after any bit of the data-out sequence is being shifted out.

In the case of a page program (PP), program OTP (POTP), dual input fast program (DIFP), subsector erase (SSE), sector erase (SE), bulk erase (BE), write status register (WRSR), write to lock register (WRLR), write enable (WREN), write disable (WRDI) or deep powerdown (DP) instruction, Chip Select (\overline{S}) must be driven High exactly at a byte boundary, otherwise the instruction is rejected, and is not executed. That is, Chip Select (\overline{S}) must driven High when the number of clock pulses after Chip Select (\overline{S}) being driven Low is an exact multiple of eight.

All attempts to access the memory array during a write status register cycle, program cycle or erase cycle are ignored, and the internal write status register cycle, program cycle or erase cycle continues unaffected.

Note: Output Hi-Z is defined as the point where data out is no longer driven.

M25PX64 Instructions

Table 5. Instruction set

Instruction	Description	One-byte instruction	Address bytes	Dummy bytes	Data bytes	
WREN	Write enable	0000 0110	06h	0	0	0
WRDI	Write disable	0000 0100	04h	0	0	0
RDID	Read identification	1001 1111	9Fh	0	0	1 to 20
טוטא	Read identification	1001 1110	9Eh	0	0	1 to 3
RDSR	Read status register	0000 0101	05h	0	0	1 to ∞
WRSR	Write status register	0000 0001	01h	0	0	1
WRLR	Write to lock register	1110 0101	E5h	3	0	1
RDLR	Read lock register	1110 1000	E8h	3	0	1
READ	Read data bytes	0000 0011	03h	3	0	1 to ∞
FAST_READ	Read data bytes at higher speed	her speed 0000 1011 0Bh 3		3	1	1 to ∞
DOFR	Dual output fast read 0011 1011		3Bh	3	1	1 to ∞
ROTP	Read OTP (read 64 bytes of OTP area)	0100 1011	4Bh	3	1	1 to 65
POTP	Program OTP (program 64 bytes of OTP area)	0100 0010	0 42h 3		0	1 to 65
PP	Page program	0000 0010	02h	3	0	1 to 256
DIFP	Dual input fast program	1010 0010	A2h	3	0	1 to 256
SSE	Subsector erase	0010 0000	20h	3	0	0
SE	Sector erase	1101 1000	D8h	3	0	0
BE	Bulk erase	1100 0111	C7h	0	0	0
DP	Deep power-down	1011 1001 B9h 0		0	0	0
RDP	Release from deep power-down	1010 1011	ABh	0	0	0

Instructions M25PX64

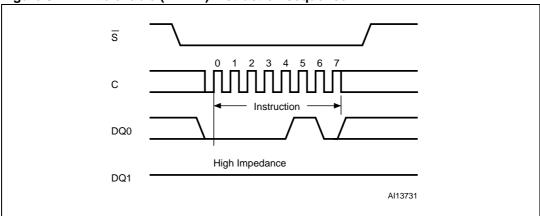
6.1 Write enable (WREN)

The write enable (WREN) instruction (Figure 8) sets the write enable latch (WEL) bit.

The write enable latch (WEL) bit must be set prior to every page program (PP), dual input fast program (DIFP), program OTP (POTP), write to lock register (WRLR), subsector erase (SSE), sector erase (SE), bulk erase (BE) and write status register (WRSR) instruction.

The write enable (WREN) instruction is entered by driving Chip Select (\overline{S}) Low, sending the instruction code, and then driving Chip Select (\overline{S}) High.





M25PX64 Instructions

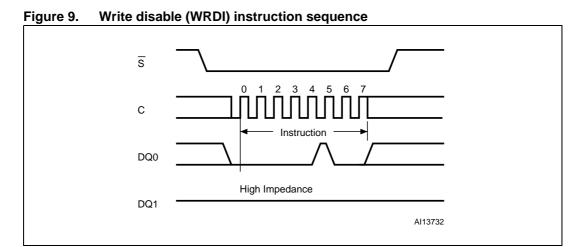
6.2 Write disable (WRDI)

The write disable (WRDI) instruction (Figure 9) resets the write enable latch (WEL) bit.

The write disable (WRDI) instruction is entered by driving Chip Select (\overline{S}) Low, sending the instruction code, and then driving Chip Select (\overline{S}) High.

The write enable latch (WEL) bit is reset under the following conditions:

- Power-up
- Write disable (WRDI) instruction completion
- Write status register (WRSR) instruction completion
- Write to lock register (WRLR) instruction completion
- Page program (PP) instruction completion
- Dual input fast program (DIFP) instruction completion
- Program OTP (POTP) instruction completion
- Subsector erase (SSE) instruction completion
- Sector erase (SE) instruction completion
- Bulk erase (BE) instruction completion



Instructions M25PX64

6.3 Read identification (RDID)

The read identification (RDID) instruction allows to read the device identification data:

- Manufacturer identification (1 byte)
- Device identification (2 bytes)
- A unique ID code (UID) (17 bytes, of which 16 available upon customer request).

The manufacturer identification is assigned by JEDEC, and has the value 20h for Numonyx. The device identification is assigned by the device manufacturer, and indicates the memory type in the first byte (71h), and the memory capacity of the device in the second byte (17h). The UID contains the length of the following data in the first byte (set to 10h) and 16 bytes of the optional customized factory data (CFD) content. The CFD bytes are read-only and can be programmed with customers data upon their demand. If the customers do not make requests, the devices are shipped with all the CFD bytes programmed to zero (00h).

Any read identification (RDID) instruction while an erase or program cycle is in progress, is not decoded, and has no effect on the cycle that is in progress.

The read identification (RDID) instruction should not be issued while the device is in deep power-down mode.

The device is first selected by driving Chip Select (\overline{S}) Low. Then, the 8-bit instruction code for the instruction is shifted in. After this, the 24-bit device identification, stored in the memory, the 8-bit CFD length followed by 16 bytes of CFD content will be shifted out on serial data output (DQ1). Each bit is shifted out during the falling edge of Serial Clock (C).

The instruction sequence is shown in Figure 10.

The read identification (RDID) instruction is terminated by driving Chip Select (\overline{S}) High at any time during data output.

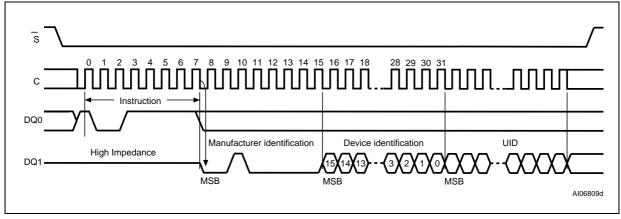
When Chip Select (\overline{S}) is driven High, the device is put in the standby power mode. Once in the standby power mode, the device waits to be selected, so that it can receive, decode and execute instructions.

Table 6. Read identification (RDID) data-out sequence

Manufacturer identification	Device identification		UID	
Wandracturer Identification	Memory type M		CFD length	CFD content
20h	71h	17h	10h	16 bytes

M25PX64 Instructions

Figure 10. Read identification (RDID) instruction sequence and data-out sequence

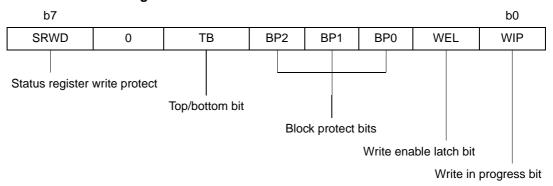


Instructions M25PX64

6.4 Read status register (RDSR)

The read status register (RDSR) instruction allows the status register to be read. The status register may be read at any time, even while a program, erase or write status register cycle is in progress. When one of these cycles is in progress, it is recommended to check the write in progress (WIP) bit before sending a new instruction to the device. It is also possible to read the status register continuously, as shown in *Figure 11*.

Table 7. Status register format



The status and control bits of the status register are as follows:

6.4.1 WIP bit

The write in progress (WIP) bit indicates whether the memory is busy with a write status register, program or erase cycle. When set to '1', such a cycle is in progress, when reset to '0' no such cycle is in progress.

6.4.2 WEL bit

The write enable latch (WEL) bit indicates the status of the internal write enable latch. When set to '1' the internal write enable latch is set, when set to '0' the internal write enable latch is reset and no write status register, program or erase instruction is accepted.

6.4.3 BP2, BP1, BP0 bits

The block protect (BP2, BP1, BP0) bits are non-volatile. They define the size of the area to be software protected against program and erase instructions. These bits are written with the write status register (WRSR) instruction. When one or more of the block protect (BP2, BP1, BP0) bits is set to '1', the relevant memory area (as defined in *Table 3*) becomes protected against page program (PP) and sector erase (SE) instructions. The block protect (BP2, BP1, BP0) bits can be written provided that the hardware protected mode has not been set. The bulk erase (BE) instruction is executed if, and only if, all block protect (BP2, BP1, BP0) bits are 0.

M25PX64 Instructions

6.4.4 Top/bottom bit

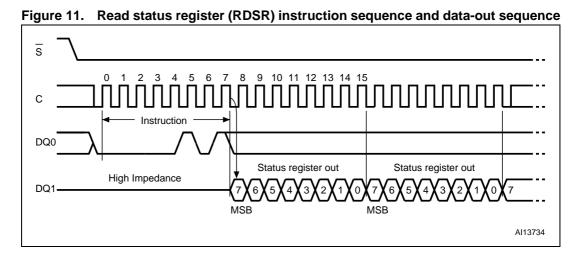
The top/bottom (TB) bit is non-volatile. It can be set and reset with the write status register (WRSR) instruction provided that the write enable (WREN) instruction has been issued. The top/bottom (TB) bit is used in conjunction with the block protect (BP0, BP1, BP2) bits to determine if the protected area defined by the block protect bits starts from the top or the bottom of the memory array:

- When top/bottom bit is reset to '0' (default value), the area protected by the block protect bits starts from the top of the memory array (see *Table 3: Protected area sizes*)
- When top/bottom bit is set to '1', the area protected by the block protect bits starts from the bottom of the memory array (see *Table 3: Protected area sizes*).

The top/bottom bit cannot be written when the SRWD bit is set to '1' and the \overline{W} pin is driven Low.

6.4.5 SRWD bit

The status register write disable (SRWD) bit is operated in conjunction with the write protect (\overline{W}/V_{PP}) signal. The status register write disable (SRWD) bit and the write protect (\overline{W}/V_{PP}) signal allow the device to be put in the hardware protected mode (when the status register write disable (SRWD) bit is set to '1', and write protect (\overline{W}/V_{PP}) is driven Low). In this mode, the non-volatile bits of the status register (SRWD, BP2, BP1, BP0) become read-only bits and the write status register (WRSR) instruction is no longer accepted for execution.



Instructions M25PX64

6.5 Write status register (WRSR)

The write status register (WRSR) instruction allows new values to be written to the status register. Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded and executed, the device sets the write enable latch (WEL).

The write status register (WRSR) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code and the data byte on serial data input (DQ0).

The instruction sequence is shown in *Figure 12*.

The write status register (WRSR) instruction has no effect on b6, b1 and b0 of the status register. b6 is always read as '0'.

Chip Select (\overline{S}) must be driven High after the eighth bit of the data byte has been latched in. If not, the write status register (WRSR) instruction is not executed. As soon as Chip Select (\overline{S}) is driven High, the self-timed write status register cycle (whose duration is t_W) is initiated. While the write status register cycle is in progress, the status register may still be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed write status register cycle, and is 0 when it is completed. When the cycle is completed, the write enable latch (WEL) is reset.

The write status register (WRSR) instruction allows the user to change the values of the block protect (BP2, BP1, BP0) bits, to define the size of the area that is to be treated as read-only, as defined in *Table 3*. The write status register (WRSR) instruction also allows the user to set and reset the status register write disable (SRWD) bit in accordance with the Write Protect (\overline{W}/V_{PP}) signal. The status register write disable (SRWD) bit and Write Protect (\overline{W}/V_{PP}) signal allow the device to be put in the hardware protected mode (HPM). The write status register (WRSR) instruction is not executed once the hardware protected mode (HPM) is entered.

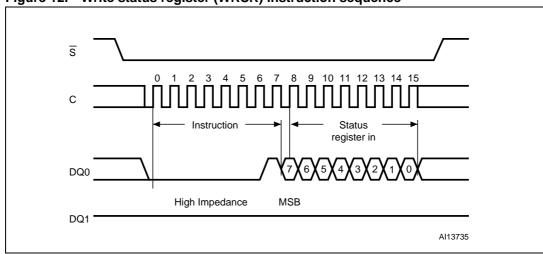


Figure 12. Write status register (WRSR) instruction sequence

N numonyx

M25PX64 Instructions

W/V _{PP}	SRWD	Mode	Write protection of	Memory content	
signal	bit	Wode	the status register	Protected area ⁽¹⁾	Unprotected area ⁽¹⁾
1	0		Status register is		
0	0		writable (if the		
1	1	Software protected (SPM)	WREN instruction has set the WEL bit) The values in the SRWD, BP2, BP1 and BP0 bits can be changed	Protected against page program, sector erase and bulk erase	Ready to accept page program and sector erase instructions
0	1	Hardware protected (HPM)	Status register is hardware write protected The values in the SRWD, BP2, BP1 and BP0 bits cannot be changed	Protected against page program, sector erase and bulk erase	Ready to accept page program and sector erase instructions

Table 8. Protection modes

The protection features of the device are summarized in Table 8.

When the status register write disable (SRWD) bit of the status register is 0 (its initial delivery state), it is possible to write to the status register provided that the write enable latch (WEL) bit has previously been set by a write enable (WREN) instruction, regardless of the whether Write Protect (\overline{W}/V_{PP}) is driven High or Low.

When the status register write disable (SRWD) bit of the status register is set to '1', two cases need to be considered, depending on the state of Write Protect (\overline{W}/V_{PP}):

- If Write Protect (W/V_{PP}) is driven High, it is possible to write to the status register provided that the write enable latch (WEL) bit has previously been set by a write enable (WREN) instruction.
- If write protect (W/V_{PP}) is driven Low, it is not possible to write to the status register even if the write enable latch (WEL) bit has previously been set by a write enable (WREN) instruction (attempts to write to the status register are rejected, and are not accepted for execution). As a consequence, all the data bytes in the memory area that are software protected (SPM) by the block protect (BP2, BP1, BP0) bits of the status register, are also hardware protected against data modification.

Regardless of the order of the two events, the hardware protected mode (HPM) can be entered:

- by setting the status register write disable (SRWD) bit after driving Write Protect (W/V_{PP}) Low
- or by driving Write Protect (W/V_{PP}) Low after setting the status register write disable (SRWD) bit.

The only way to exit the hardware protected mode (HPM) once entered is to pull Write Protect (\overline{W}/V_{PP}) High.

If Write Protect (\overline{W}/V_{PP}) is permanently tied High, the hardware protected mode (HPM) can never be activated, and only the software protected mode (SPM), using the block protect (BP2, BP1, BP0) bits of the status register, can be used.

As defined by the values in the block protect (BP2, BP1, BP0) bits of the status register, as shown in Table 3.

Instructions M25PX64

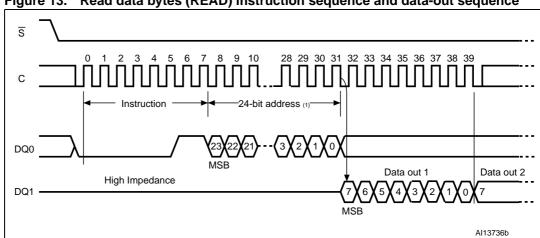
6.6 Read data bytes (READ)

The device is first selected by driving Chip Select (\overline{S}) Low. The instruction code for the read data bytes (READ) instruction is followed by a 3-byte address (A23-A0), each bit being latched-in during the rising edge of Serial Clock (C). Then the memory contents, at that address, is shifted out on serial data output (DQ1), each bit being shifted out, at a maximum frequency f_R, during the falling edge of Serial Clock (C).

The instruction sequence is shown in *Figure 13*.

The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. The whole memory can, therefore, be read with a single read data bytes (READ) instruction. When the highest address is reached, the address counter rolls over to 000000h, allowing the read sequence to be continued indefinitely.

The read data bytes (READ) instruction is terminated by driving Chip Select (S) High. Chip Select (\overline{S}) can be driven High at any time during data output. Any read data bytes (READ) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.



Read data bytes (READ) instruction sequence and data-out sequence Figure 13.

1. Address bit A23 is don't care.

6.7 Read data bytes at higher speed (FAST_READ)

The device is first selected by driving Chip Select (\overline{S}) Low. The instruction code for the read data bytes at higher speed (FAST_READ) instruction is followed by a 3-byte address (A23-A0) and a dummy byte, each bit being latched-in during the rising edge of Serial Clock (C). Then the memory contents, at that address, are shifted out on serial data output (DQ1) at a maximum frequency f_C , during the falling edge of Serial Clock (C).

The instruction sequence is shown in Figure 14.

The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. The whole memory can, therefore, be read with a single read data bytes at higher speed (FAST_READ) instruction. When the highest address is reached, the address counter rolls over to 000000h, allowing the read sequence to be continued indefinitely.

The read data bytes at higher speed (FAST_READ) instruction is terminated by driving Chip Select (\overline{S}) High. Chip Select (\overline{S}) can be driven High at any time during data output. Any read data bytes at higher speed (FAST_READ) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

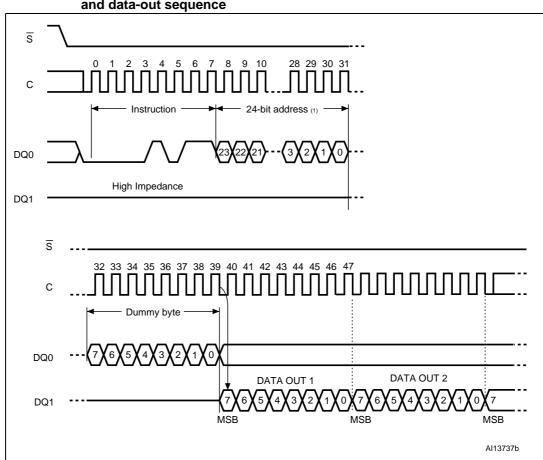


Figure 14. Read data bytes at higher speed (FAST_READ) instruction sequence and data-out sequence

1. Address bit A23 is don't care.

Instructions M25PX64

6.8 **Dual output fast read (DOFR)**

The dual output fast read (DOFR) instruction is very similar to the read data bytes at higher speed (FAST_READ) instruction, except that the data are shifted out on two pins (pin DQ0 and pin DQ1) instead of only one. Outputting the data on two pins instead of one doubles the data transfer bandwidth compared to the read data bytes at higher speed (FAST_READ) instruction.

The device is first selected by driving Chip Select (\overline{S}) Low. The instruction code for the dual output fast read instruction is followed by a 3-byte address (A23-A0) and a dummy byte, each bit being latched-in during the rising edge of Serial Clock (C). Then the memory contents, at that address, are shifted out on DQ0 and DQ1 at a maximum frequency f_C, during the falling edge of Serial Clock (C).

The instruction sequence is shown in Figure 15.

The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out on DQ0 and DQ1. The whole memory can, therefore, be read with a single dual output fast read (DOFR) instruction. When the highest address is reached, the address counter rolls over to 00 0000h, so that the read sequence can be continued indefinitely.

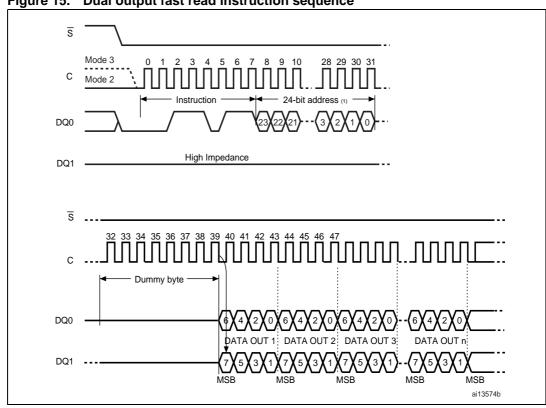


Figure 15. Dual output fast read instruction sequence

Address bit A23 is don't care.

6.9 Read lock register (RDLR)

The device is first selected by driving Chip Select (\overline{S}) Low. The instruction code for the read lock register (RDLR) instruction is followed by a 3-byte address (A23-A0) pointing to any location inside the concerned sector. Each address bit is latched-in during the rising edge of Serial Clock (C). Then the value of the lock register is shifted out on serial data output (DQ1), each bit being shifted out, at a maximum frequency f_C , during the falling edge of Serial Clock (C).

The instruction sequence is shown in *Figure 16*.

The read lock register (RDLR) instruction is terminated by driving Chip Select (\overline{S}) High at any time during data output.

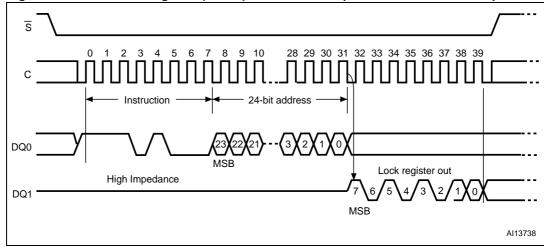
Any read lock register (RDLR) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

Table 9. Lock register out⁽¹⁾

Bit	Bit name Value Function					
b7-b2	Reserved					
b1	b1 Sector lock down		The write lock and lock down bits cannot be changed. Once a '1' is written to the lock down bit it cannot be cleared to '0', except by a power-up.			
		'0'	The write lock and lock down bits can be changed by writing new values to them.			
h0			Write, program and erase operations in this sector will not be executed. The memory contents will not be changed.			
b0	Sector write lock	'0'	Write, program and erase operations in this sector are executed and will modify the sector contents.			

^{1.} Values of (b1, b0) after power-up are defined in Section 7: Power-up and power-down.

Figure 16. Read lock register (RDLR) instruction sequence and data-out sequence



Instructions M25PX64

Read OTP (ROTP) 6.10

The device is first selected by driving Chip Select (\overline{S}) Low. The instruction code for the read OTP (ROTP) instruction is followed by a 3-byte address (A23- A0) and a dummy byte. Each bit is latched in on the rising edge of Serial Clock (C).

Then the memory contents at that address are shifted out on serial data output (DQ1). Each bit is shifted out at the maximum frequency, f_Cmax, on the falling edge of Serial Clock (C). The instruction sequence is shown in *Figure 17*.

The address is automatically incremented to the next higher address after each byte of data is shifted out.

There is no rollover mechanism with the read OTP (ROTP) instruction. This means that the read OTP (ROTP) instruction must be sent with a maximum of 65 bytes to read, since once the 65th byte has been read, the same (65th) byte keeps being read on the DQ1 pin.

The read OTP (ROTP) instruction is terminated by driving Chip Select (\overline{S}) High. Chip Select (S) can be driven High at any time during data output. Any read OTP (ROTP) instruction issued while an erase, program or write cycle is in progress, is rejected without having any effect on the cycle that is in progress.

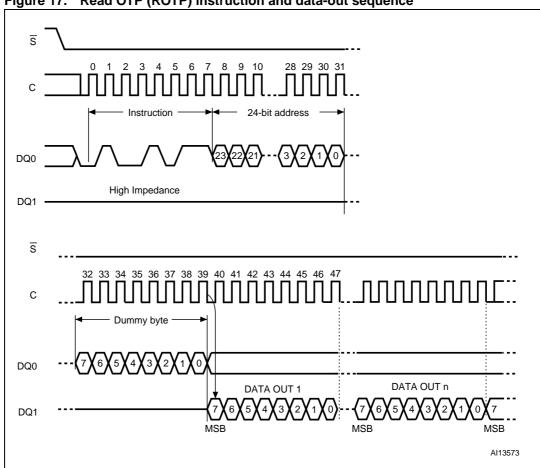


Figure 17. Read OTP (ROTP) instruction and data-out sequence

- 1. A23 to A7 are don't care.
- 2. $1 \le n \le 65$.

6.11 Page program (PP)

The page program (PP) instruction allows bytes to be programmed in the memory (changing bits from '1' to '0'). Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded, the device sets the write enable latch (WEL).

The page program (PP) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code, three address bytes and at least one data byte on serial data input (DQ0). If the 8 least significant address bits (A7-A0) are not all zero, all transmitted data that goes beyond the end of the current page are programmed from the start address of the same page (from the address whose 8 least significant bits (A7-A0) are all zero). Chip Select (\overline{S}) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in *Figure 18*.

If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page.

For optimized timings, it is recommended to use the page program (PP) instruction to program all consecutive targeted bytes in a single sequence versus using several page program (PP) sequences with each containing only a few bytes (see *Table 17: AC characteristics*).

Chip Select (\overline{S}) must be driven High after the eighth bit of the last data byte has been latched in, otherwise the page program (PP) instruction is not executed.

As soon as Chip Select (\overline{S}) is driven High, the self-timed page program cycle (whose duration is t_{PP}) is initiated. While the page program cycle is in progress, the status register may be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed page program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the write enable latch (WEL) bit is reset.

A page program (PP) instruction applied to a page which is protected by the block protect (BP2, BP1, BP0) bits (see *Table 3* and *Table 4*) is not executed.

Instructions M25PX64

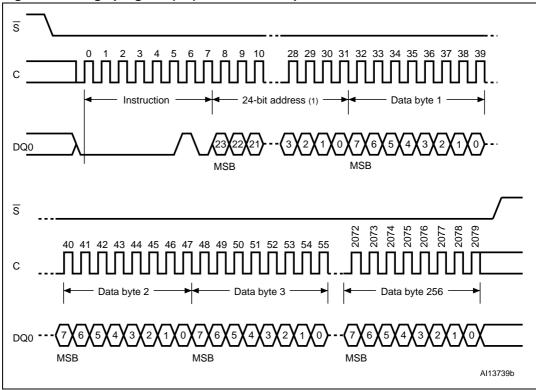


Figure 18. Page program (PP) instruction sequence

1. Address bit A23 is don't care.

6.12 Dual input fast program (DIFP)

The dual input fast program (DIFP) instruction is very similar to the page program (PP) instruction, except that the data are entered on two pins (pin DQ0 and pin DQ1) instead of only one. Inputting the data on two pins instead of one doubles the data transfer bandwidth compared to the page program (PP) instruction.

The dual input fast program (DIFP) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code, three address bytes and at least one data byte on serial data input (DQ0).

If the 8 least significant address bits (A7-A0) are not all zero, all transmitted data that goes beyond the end of the current page are programmed from the start address of the same page (from the address whose 8 least significant bits (A7-A0) are all zero). Chip Select (\overline{S}) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in Figure 19.

If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes in the same page.

For optimized timings, it is recommended to use the dual input fast program (DIFP) instruction to program all consecutive targeted bytes in a single sequence rather to using several dual input fast program (DIFP) sequences each containing only a few bytes (see *Table 17: AC characteristics*).

Chip Select (\overline{S}) must be driven High after the eighth bit of the last data byte has been latched in, otherwise the dual input fast program (DIFP) instruction is not executed.

As soon as Chip Select (\overline{S}) is driven High, the self-timed page program cycle (whose duration is t_{PP}) is initiated. While the dual input fast program (DIFP) cycle is in progress, the status register may be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed page program cycle, and 0 when it is completed. At some unspecified time before the cycle is completed, the write enable latch (WEL) bit is reset.

A dual input fast program (DIFP) instruction applied to a page that is protected by the block protect (BP2, BP1, BP0) bits (see *Table 2* and *Table 3*) is not executed.

Instructions M25PX64

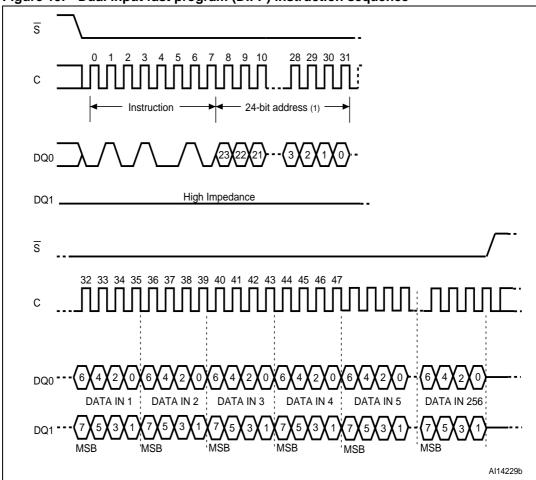


Figure 19. Dual input fast program (DIFP) instruction sequence

1. Address bit A23 is don't care.

6.13 Program OTP instruction (POTP)

The program OTP instruction (POTP) is used to program at most 64 bytes to the OTP memory area (by changing bits from '1' to '0', only). Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded, the device sets the write enable latch (WEL) bit.

The program OTP instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction opcode, three address bytes and at least one data byte on serial data input (DQ0).

Chip Select (\overline{S}) must be driven High after the eighth bit of the last data byte has been latched in, otherwise the program OTP instruction is not executed.

There is no rollover mechanism with the program OTP (POTP) instruction. This means that the program OTP (POTP) instruction must be sent with a maximum of 65 bytes to program, once all 65 bytes have been latched in, any following byte will be discarded.

The instruction sequence is shown in Figure 20.

As soon as Chip Select (\overline{S}) is driven High, the self-timed page program cycle (whose duration is t_{PP}) is initiated. While the program OTP cycle is in progress, the status register may be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed program OTP cycle, and it is 0 when it is completed. At some unspecified time before the cycle is complete, the write enable latch (WEL) bit is reset.

To lock the OTP memory:

Bit 0 of the OTP control byte, that is byte 64, (see *Figure 21*) is used to permanently lock the OTP memory array.

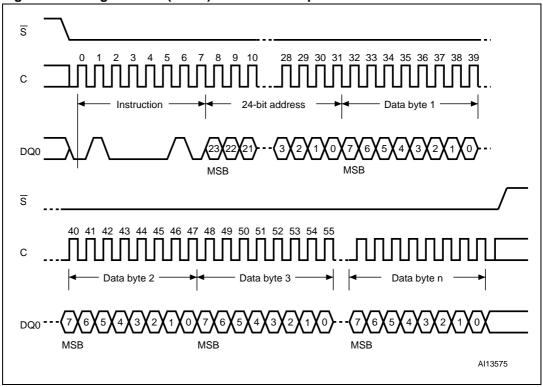
- When bit 0 of byte 64 = '1', the 64 bytes of the OTP memory array can be programmed.
- When bit 0 of byte 64 = '0', the 64 bytes of the OTP memory array are read-only and cannot be programmed anymore.

Once a bit of the OTP memory has been programmed to '0', it can no longer be set to '1'. Therefore, as soon as bit 0 of byte 64 (control byte) is set to '0', the 64 bytes of the OTP memory array become read-only in a permanent way.

Any program OTP (POTP) instruction issued while an erase, program or write cycle is in progress is rejected without having any effect on the cycle that is in progress.

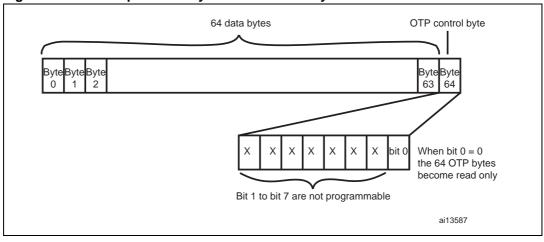
Instructions M25PX64

Figure 20. Program OTP (POTP) instruction sequence



- 1. A23 to A7 are don't care.
- $2. \quad 1 \leq n \leq 65.$

Figure 21. How to permanently lock the 64 OTP bytes



Write to lock register (WRLR) 6.14

The write to lock register (WRLR) instruction allows bits to be changed in the lock registers. Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded, the device sets the write enable latch (WEL).

The write to lock register (WRLR) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code, three address bytes (pointing to any address in the targeted sector and one data byte on serial data input (DQ0). The instruction sequence is shown in Figure 22. Chip Select $\overline{(S)}$ must be driven High after the eighth bit of the data byte has been latched in, otherwise the write to lock register (WRLR) instruction is not executed.

Lock register bits are volatile, and therefore do not require time to be written. When the write to lock register (WRLR) instruction has been successfully executed, the write enable latch (WEL) bit is reset after a delay time less than t_{SHSL} minimum value.

Any write to lock register (WRLR) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

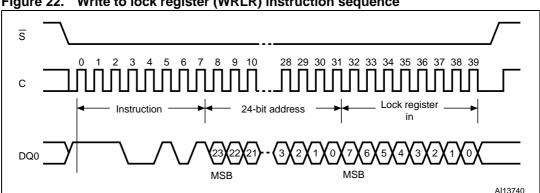


Figure 22. Write to lock register (WRLR) instruction sequence

Lock register in⁽¹⁾ Table 10.

Sector	Bit	Value
	b7-b2	,0,
All sectors	b1 Sector lock down bit value (refer to <i>Table 9</i>)	
	b0	Sector write lock bit value (refer to Table 9)

1. Values of (b1, b0) after power-up are defined in Section 7: Power-up and power-down.

Instructions M25PX64

6.15 Subsector erase (SSE)

The subsector erase (SSE) instruction sets to '1' (FFh) all bits inside the chosen subsector. Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded, the device sets the write enable latch (WEL).

The subsector erase (SSE) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code, and three address bytes on serial data input (DQ0). Any address inside the subsector (see *Table 4*) is a valid address for the subsector erase (SSE) instruction. Chip Select (\overline{S}) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in Figure 23.

Chip Select (\overline{S}) must be driven High after the eighth bit of the last address byte has been latched in, otherwise the subsector erase (SSE) instruction is not executed. As soon as Chip Select (\overline{S}) is driven High, the self-timed subsector erase cycle (whose duration is t_{SSE}) is initiated. While the subsector erase cycle is in progress, the status register may be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed subsector erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is complete, the write enable latch (WEL) bit is reset.

A subsector erase (SSE) instruction issued to a sector that is hardware or software protected, is not executed.

Any subsector erase (SSE) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

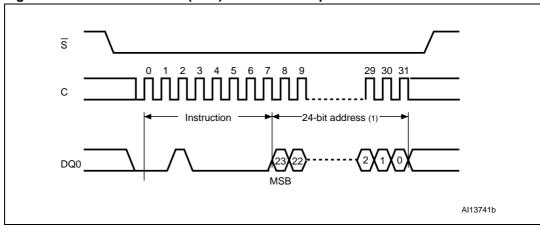


Figure 23. Subsector erase (SSE) instruction sequence

1. Address bit A23 is don't care.

6.16 Sector erase (SE)

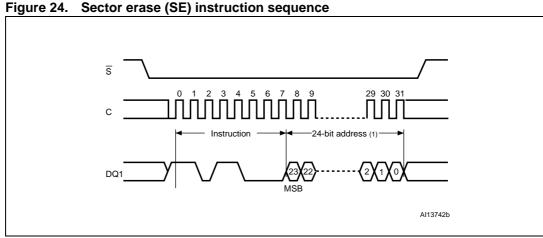
The sector erase (SE) instruction sets to '1' (FFh) all bits inside the chosen sector. Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded, the device sets the write enable latch (WEL).

The sector erase (SE) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code, and three address bytes on serial data input (DQ0). Any address inside the sector (see *Table 4*) is a valid address for the sector erase (SE) instruction. Chip Select (\overline{S}) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in Figure 24.

Chip Select (\overline{S}) must be driven High after the eighth bit of the last address byte has been latched in, otherwise the sector erase (SE) instruction is not executed. As soon as Chip Select (\overline{S}) is driven High, the self-timed sector erase cycle (whose duration is t_{SE}) is initiated. While the sector erase cycle is in progress, the status register may be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed sector erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the write enable latch (WEL) bit is reset.

A sector erase (SE) instruction applied to a page which is protected by the block protect (BP2, BP1, BP0) bits (see *Table 3* and *Table 4*) is not executed.



Address bit A23 is don't care.

Instructions M25PX64

6.17 Bulk erase (BE)

The bulk erase (BE) instruction sets all bits to '1' (FFh). Before it can be accepted, a write enable (WREN) instruction must previously have been executed. After the write enable (WREN) instruction has been decoded, the device sets the write enable latch (WEL).

The bulk erase (BE) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code on serial data input (DQ0). Chip Select (S) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in Figure 25.

Chip Select (S) must be driven High after the eighth bit of the instruction code has been latched in, otherwise the bulk erase instruction is not executed. As soon as Chip Select (S) is driven High, the self-timed bulk erase cycle (whose duration is t_{BE}) is initiated. While the bulk erase cycle is in progress, the status register may be read to check the value of the write in progress (WIP) bit. The write in progress (WIP) bit is 1 during the self-timed bulk erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the write enable latch (WEL) bit is reset.

The bulk erase (BE) instruction is executed only if all block protect (BP2, BP1, BP0) bits are 0. The bulk erase (BE) instruction is ignored if one, or more, sectors are protected.

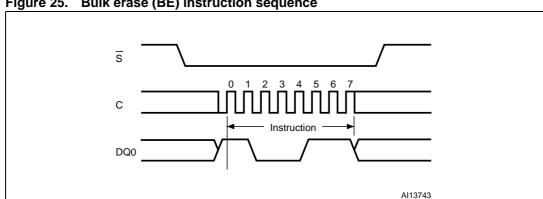


Figure 25. Bulk erase (BE) instruction sequence

6.18 Deep power-down (DP)

Executing the deep power-down (DP) instruction is the only way to put the device in the lowest consumption mode (the deep power-down mode). It can also be used as a software protection mechanism, while the device is not in active use, as in this mode, the device ignores all write, program and erase instructions.

Driving Chip Select (\overline{S}) High deselects the device, and puts the device in the standby power mode (if there is no internal cycle currently in progress). But this mode is not the deep power-down mode. The deep power-down mode can only be entered by executing the deep power-down (DP) instruction, subsequently reducing the standby current (from I_{CC1} to I_{CC2} , as specified in *Table 16*).

To take the device out of deep power-down mode, the release from deep power-down (RDP) instruction must be issued. No other instruction must be issued while the device is in deep power-down mode.

The deep power-down mode automatically stops at power-down, and the device always powers up in the standby power mode.

The deep power-down (DP) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code on serial data input (DQ0). Chip Select (\overline{S}) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in Figure 26.

Chip Select (\overline{S}) must be driven High after the eighth bit of the instruction code has been latched in, otherwise the deep power-down (DP) instruction is not executed. As soon as Chip Select (\overline{S}) is driven High, it requires a delay of t_{DP} before the supply current is reduced to t_{CC2} and the deep power-down mode is entered.

Any deep power-down (DP) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

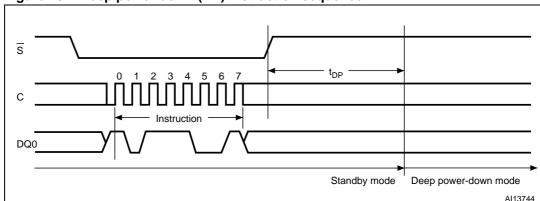


Figure 26. Deep power-down (DP) instruction sequence

Instructions M25PX64

6.19 Release from deep power-down (RDP)

Once the device has entered the deep power-down mode, all instructions are ignored except the release from deep power-down (RDP) instruction. Executing this instruction takes the device out of the deep power-down mode.

The release from deep power-down (RDP) instruction is entered by driving Chip Select (\overline{S}) Low, followed by the instruction code on serial data input (DQ0). Chip Select (\overline{S}) must be driven Low for the entire duration of the sequence.

The instruction sequence is shown in Figure 27.

The release from deep power-down (RDP) instruction is terminated by driving Chip Select (\overline{S}) High. Sending additional clock cycles on Serial Clock (C), while Chip Select (\overline{S}) is driven Low, cause the instruction to be rejected, and not executed.

After Chip Select (\overline{S}) has been driven High, followed by a delay, t_{RDP} the device is put in the standby mode. Chip Select (\overline{S}) must remain High at least until this period is over. The device waits to be selected, so that it can receive, decode and execute instructions.

Any release from deep power-down (RDP) instruction, while an erase, program or write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

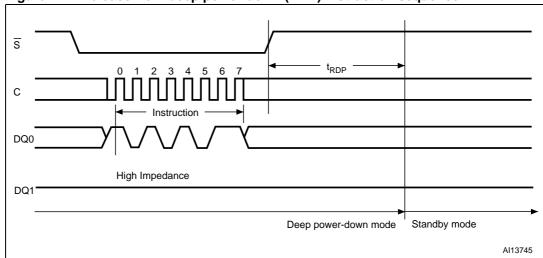


Figure 27. Release from deep power-down (RDP) instruction sequence

53/66

7 Power-up and power-down

At power-up and power-down, the device must not be selected (that is Chip Select (\overline{S}) must follow the voltage applied on V_{CC}) until V_{CC} reaches the correct value:

- V_{CC}(min) at power-up, and then for a further delay of t_{VSI}
- V_{SS} at power-down.

A safe configuration is provided in Section 3: SPI modes.

To avoid data corruption and inadvertent write operations during power-up, a power on reset (POR) circuit is included. The logic inside the device is held reset while V_{CC} is less than the power on reset (POR) threshold voltage, V_{WI} – all operations are disabled, and the device does not respond to any instruction.

Moreover, the device ignores all write enable (WREN), page program (PP), dual input fast program (DIFP), program OTP (POTP), subsector erase (SSE), sector erase (SE), bulk erase (BE), write status register (WRSR) and write to lock register (WRLR) instructions until a time delay of t_{PUW} has elapsed after the moment that V_{CC} rises above the V_{WI} threshold. However, the correct operation of the device is not guaranteed if, by this time, V_{CC} is still below V_{CC} (min). No write status register, program or erase instructions should be sent until the later of:

- t_{PUW} after V_{CC} has passed the V_{WI} threshold
- t_{VSL} after V_{CC} has passed the V_{CC}(min) level.

These values are specified in Table 11.

If the time, t_{VSL} , has elapsed, after V_{CC} rises above V_{CC} (min), the device can be selected for read instructions even if the t_{PLIW} delay has not yet fully elapsed.

After power-up, the device is in the following state:

- The device is in the standby power mode (not the deep power-down mode)
- The write enable latch (WEL) bit is reset
- The write in progress (WIP) bit is reset
- The lock registers are configured as: (write lock bit, lock down bit) = (0,0).

Normal precautions must be taken for supply line decoupling, to stabilize the V_{CC} supply. Each device in a system should have the V_{CC} line decoupled by a suitable capacitor close to the package pins (generally, this capacitor is of the order of 100 nF).

At power-down, when V_{CC} drops from the operating voltage, to below the power on reset (POR) threshold voltage, V_{WI} , all operations are disabled and the device does not respond to any instruction (the designer needs to be aware that if power-down occurs while a write, program or erase cycle is in progress, some data corruption may result).

V_{PPH} must be applied only when V_{CC} is stable and in the V_{CC}(min) to V_{CC}(max) voltage range.

Initial delivery state M25PX64

Figure 28. Power-up timing

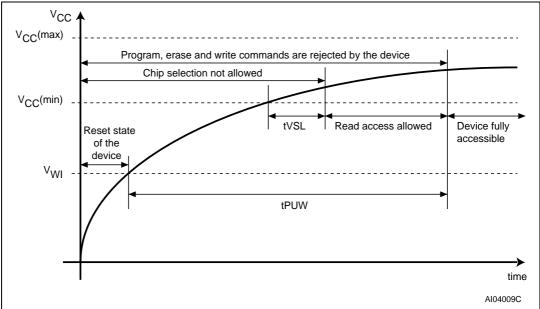


Table 11. Power-up timing and V_{WI} threshold

Symbol	Parameter	Min	Max	Unit
t _{VSL} ⁽¹⁾	V _{CC} (min) to \overline{S} Low	30		μs
t _{PUW} ⁽¹⁾	Time delay to write instruction	1	10	ms
V _{WI} ⁽¹⁾	Write inhibit voltage	1.5	2.5	V

^{1.} These parameters are characterized only.

8 Initial delivery state

The device is delivered with the memory array erased: all bits are set to '1' (each byte contains FFh). The status register contains 00h (all status register bits are 0).

M25PX64 Maximum ratings

9 Maximum ratings

Stressing the device outside the ratings listed in *Table 12: Absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and operation of the device at these, or any other conditions outside those indicated in the operating sections of this specification, is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the Numonyx SURE program and other relevant quality documents.

Table 12. Absolute maximum ratings

Symbol	Parameter	Min	Max	Unit
T _{STG}	Storage temperature	-65	150	°C
T _{LEAD}	Lead temperature during soldering		see ⁽¹⁾	°C
V _{IO}	Input and output voltage (with respect to ground)	-0.6	V _{CC} + 0.6	V
V _{CC}	Supply voltage	-0.6	4.0	V
V _{PP}	Fast program/erase voltage	-0.2	10.0	V
V _{ESD}	Electrostatic discharge voltage (human body model) ⁽²⁾	-2000	2000	V

Compliant with JEDEC Std J-STD-020C (for small body, Sn-Pb or Pb assembly), the Numonyx ECOPACK® 7191395 specification, and the European directive on Restrictions on Hazardous Substances (RoHS) 2002/95/EU.

^{2.} JEDEC Std JESD22-A114A (C1 = 100 pF, R1 = 1500 Ω , R2 = 500 Ω).

10 DC and AC parameters

This section summarizes the operating and measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC characteristics tables that follow are derived from tests performed under the measurement conditions summarized in the relevant tables. Designers should check that the operating conditions in their circuit match the measurement conditions when relying on the quoted parameters.

Table 13. Operating conditions

Symbol	Parameter	Min	Тур	Max	Unit
V _{CC}	Supply voltage	2.7		3.6	V
V _{PPH}	Supply voltage on V _{PP} pin for fast bulk erase mode	8.5		9.5	V
T _A	Ambient operating temperature	-40		85	°C
T _{AVPP}	Ambient operating temperature for fast bulk erase mode	15	25	35	°C

Table 14. AC measurement conditions

Symbol	Parameter	Min	Max	Unit
C _L	Load capacitance	3	pF	
	Input rise and fall times		5	ns
	Input pulse voltages	0.2V _{CC} t	0.2V _{CC} to 0.8V _{CC}	
	Input timing reference voltages	0.3V _{CC} to 0.7V _{CC}		V
	Output timing reference voltages	V _C	V	

Figure 29. AC measurement I/O waveform

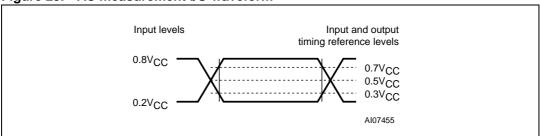


Table 15. Capacitance⁽¹⁾

Symbol	Parameter	Test condition	Min	Max	Unit
C _{IN/OUT}	Input/output capacitance (DQ0/DQ1)	V _{OUT} = 0 V		8	pF
C _{IN}	Input capacitance (other pins)	$V_{IN} = 0 V$		6	pF

^{1.} Sampled only, not 100% tested, at T_A =25 °C and a frequency of 33 MHz.

Table 16. DC characteristics

Symbol	Parameter	Test condition (in addition to those in <i>Table 13</i>)	Min	Max	Unit
ILI	Input leakage current			± 2	μΑ
I _{LO}	Output leakage current			± 2	μΑ
I _{CC1}	Standby current	$\overline{S} = V_{CC}, V_{IN} = V_{SS} \text{ or } V_{CC}$		50	μΑ
I _{CC2}	Deep Power-down current	$\overline{S} = V_{CC}, V_{IN} = V_{SS} \text{ or } V_{CC}$		10	μΑ
	Operating current (READ)	$C = 0.1V_{CC} / 0.9V_{CC}$ at 75 MHz, DQ1 = open		12	mA
I _{CC3}	Operating current (READ)	$C = 0.1V_{CC} / 0.9V_{CC}$ at 33 MHz, DQ1 = open		4	mA
	Operating current (DOFR)	$C = 0.1V_{CC} / 0.9V_{CC}$ at 75 MHz, DQ1 = open		15	mA
-	Operating current (PP)	$\overline{S} = V_{CC}$		15	mA
I _{CC4}	Operating current (DIFP)	S = V _{CC}		15	mA
I _{CC5}	Operating current (WRSR)	$\overline{S} = V_{CC}$		15	mA
I _{CC6}	Operating current (SE)	S = V _{CC}		15	mA
I _{CC7}	Operating current (BE)	S = V _{CC}		15	mA
I _{CCPP}	Operating current for fast bulk erase mode	$\overline{S} = V_{CC}, V_{PP} = V_{PPH}$		20	mA
I _{PP}	V _{PP} operating current in fast bulk erase mode	$\overline{S} = V_{CC}, V_{PP} = V_{PPH}$		20	mA
V _{IL}	Input low voltage		- 0.5	0.3V _{CC}	V
V_{IH}	Input high voltage		0.7V _{CC}	V _{CC} +0.4	V
V _{OL}	Output low voltage	I _{OL} = 1.6 mA		0.4	V
V _{OH}	Output high voltage	I _{OH} = -100 μA	V _{CC} -0.2		V

Table 17. AC characteristics⁽¹⁾

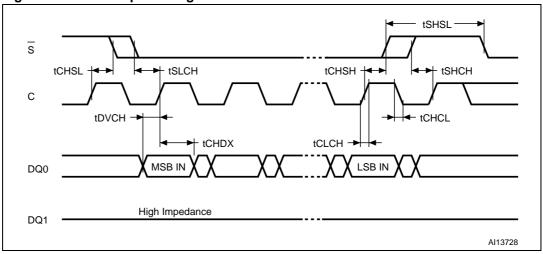
	Test conditions specified in <i>Table 13</i> and <i>Table 14</i>								
Symbol	Alt.	Parameter	Max	Unit					
f _C	Clock frequency for the following instructions: DOFR, DIFP, FAST_READ, f _C f _C SSE, SE, BE, DP, WREN, WRDI, RDID, RDSR, WRSR, ROTP, PP, POTP, WRLR, RDLR, RDP		D.C.		75	MHz			
f _R		Clock frequency for read instructions	D.C.		33	MHz			
t _{CH} ⁽³⁾	t _{CLH}	Clock High time	6			ns			
t _{CL} ⁽²⁾	t _{CLL}	Clock Low time	6			ns			
t _{CLCH} ⁽⁴⁾		Clock rise time ⁽⁵⁾ (peak to peak)	0.1			V/ns			
t _{CHCL} ⁽⁴⁾		Clock fall time ⁽⁵⁾ (peak to peak)	0.1			V/ns			
t _{SLCH}	t _{CSS}	S active setup time (relative to C)	5			ns			
t _{CHSL}		S not active hold time (relative to C)	5			ns			
t _{DVCH}	t _{DSU}	Data in setup time	2			ns			
t _{CHDX}	t _{DH}	Data in hold time	5			ns			
t _{CHSH}		S active hold time (relative to C)	5			ns			
t _{SHCH}		S not active setup time (relative to C)	5			ns			
t _{SHSL}	t _{CSH}	S deselect time	80			ns			
t _{SHQZ} ⁽⁴⁾	t _{DIS}	Output disable time			8	ns			
.	+	Clock Low to Output valid under 30 pF			8	ns			
t _{CLQV}	t _V	Clock Low to Output valid under 10 pF			6	ns			
t _{CLQX}	t _{HO}	Output hold time	0			ns			
t _{HLCH}		HOLD setup time (relative to C)	5			ns			
t _{CHHH}		HOLD hold time (relative to C)	5			ns			
t _{HHCH}		HOLD setup time (relative to C)	5			ns			
t _{CHHL}		HOLD hold time (relative to C)	5			ns			
t _{HHQX} ⁽⁴⁾	t _{LZ}	HOLD to Output Low-Z			8	ns			
t _{HLQZ} ⁽⁴⁾	t _{HZ}	HOLD to Output High-Z			8	ns			
t _{WHSL} ⁽⁶⁾		Write protect setup time	20			ns			
t _{SHWL} ⁽⁶⁾		Write protect hold time	100			ns			
t _{VPPHSL} ⁽⁷⁾		Enhanced program supply voltage High (V _{PPH}) to Chip Select Low	200			ns			
t _{DP} ⁽⁴⁾		S High to deep power-down mode			3	μs			
t _{RDP} ⁽⁴⁾		S High to standby mode			30	μs			

Test conditions specified in <i>Table 13</i> and <i>Table 14</i>								
Symbol Alt		Parameter	Min	Typ ⁽²⁾	Max	Unit		
t _W		Write status register cycle time		1.3	15	ms		
		Page program cycle time (256 bytes)		0.8				
t _{PP} ⁽⁸⁾		Page program cycle time (n bytes)		$int(n/8) \times 0.025^{(9)}$	5	ms		
		Program OTP cycle time (64 bytes)		0.2		ms		
t _{SSE}		Subsector erase cycle time		70	150	ms		
t _{SE}		Sector erase cycle time		0.7	3	s		
		Bulk erase cycle time		68	160			
t _{BE}		Bulk erase cycle time (V _{PP} = V _{PPH})		35	160	S		

AC characteristics⁽¹⁾ (continued) Table 17

- 1. Preliminary data.
- 2. Typical values given for $T_A = 25^{\circ}$ C.
- 3. $t_{CH} + t_{CL}$ must be greater than or equal to 1/ f_{C} .
- 4. Value guaranteed by characterization, not 100% tested in production.
- 5. Expressed as a slew-rate.
- 6. Only applicable as a constraint for a WRSR instruction when SRWD is set to '1'.
- V_{PPH} should be kept at a valid level until the program or erase operation has completed and its result (success or failure) is known.
- 8. When using the page program (PP) instruction to program consecutive bytes, optimized timings are obtained with one sequence including all the bytes versus several sequences of only a few bytes (1 \leq n \leq 256).
- 9. int(A) corresponds to the upper integer part of A. For example int(12/8) = 2, int(32/8) = 4 int(15.3) = 16.

Figure 30. Serial input timing



59/66

Figure 31. Write protect setup and hold timing during WRSR when SRWD=1

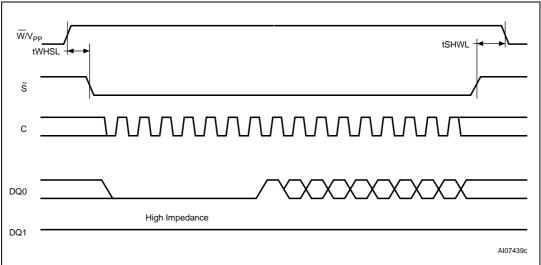


Figure 32. Hold timing

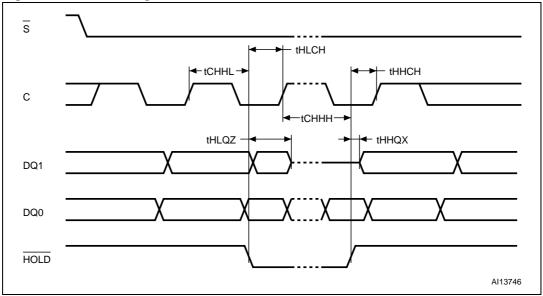


Figure 33. Output timing

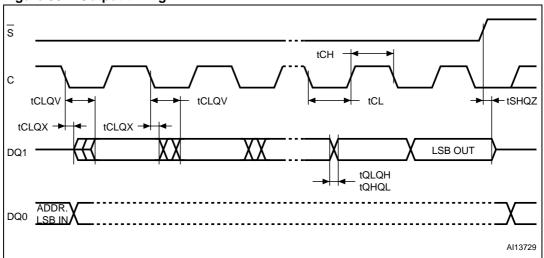
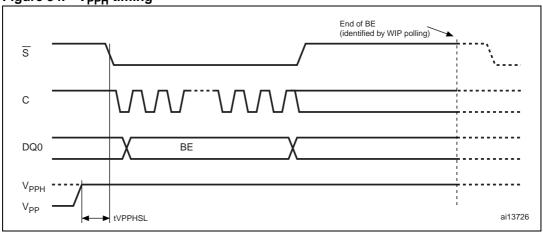


Figure 34. V_{PPH} timing



Numonyx 61/66

Package mechanical M25PX64

11 Package mechanical

In order to meet environmental requirements, Numonyx offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label.

□ ddd

D2

VDFPN-02

Figure 35. VDFPN8 (MLP8) 8-lead very thin dual flat package no lead, 8 × 6 mm, package outline

- 1. Drawing is not to scale.
- 2. The circle in the top view of the package indicates the position of pin 1.

Table 18. VDFPN8 (MLP8) 8-lead very thin dual flat package no lead, 8 × 6 mm, package mechanical data

Symbol	Millimeters			Inches			
Symbol	Тур	Min	Max	Тур	Min	Max	
А	0.85		1.00	0.033		0.039	
A1		0.00	0.05		0.000	0.002	
b	0.40	0.35	0.48	0.016	0.014	0.019	
D	8.00			0.315			
D2	5.16		(1)	0.203			
ddd			0.05			0.002	
E	6.00			0.236			
E2	4.80			0.189			
е	1.27	_	-	0.050	_	_	
K		0.82			0.032		
L	0.50	0.45	0.60	0.020	0.018	0.024	
L1			0.15			0.006	
N		8			8		

^{1.} D2 Max must not exceed $(D - K - 2 \times L)$.

M25PX64 Package mechanical

Figure 36. SO16 wide - 16-lead plastic small outline, 300 mils body width, package outline

1. Drawing is not to scale.

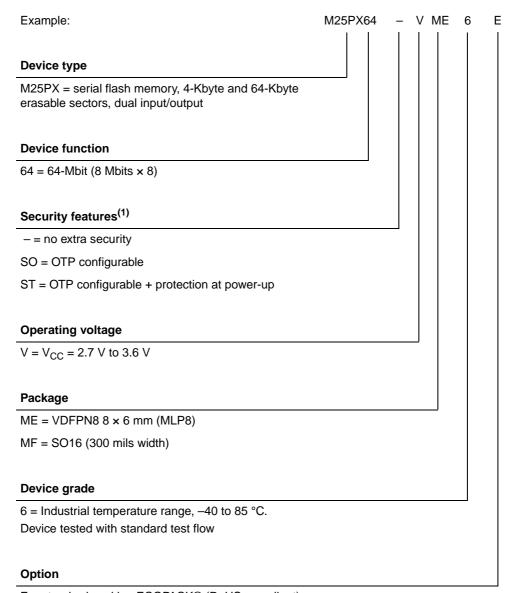
Table 19. SO16 wide - 16-lead plastic small outline, 300 mils body width, mechanical data

Symbol		Millimeters		Inches			
Symbol	Тур	Min	Max	Тур	Min	Max	
А		2.35	2.65		0.093	0.104	
A1		0.10	0.30		0.004	0.012	
В		0.33	0.51		0.013	0.020	
С		0.23	0.32		0.009	0.013	
D		10.10	10.50		0.398	0.413	
E		7.40	7.60		0.291	0.299	
е	1.27	_	-	0.050	-	-	
Н		10.00	10.65		0.394	0.419	
h		0.25	0.75		0.010	0.030	
L		0.40	1.27		0.016	0.050	
θ		0°	8°		0°	8°	
ddd			0.10			0.004	

Ordering information M25PX64

12 Ordering information

Table 20. Ordering information scheme



E = standard packing ECOPACK® (RoHS compliant)

F = tape and reel packing ECOPACK® (RoHS compliant)

1. Secure options are available upon customer request.

Note: For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact your nearest Numonyx sales office.

Numonyx

M25PX64 Revision history

13 Revision history

Table 21. Document revision history

Date	Revision	Changes
05-Nov-2007	1	Initial release.
25-Mar-2008	2	Updated the minimum value for t _{SHSL} in <i>Table 17: AC characteristics</i> . Applied Numonyx branding.

Numonyx 65/66

Please Read Carefully:

INFORMATION IN THIS DOCUMENT IS PROVIDED IN CONNECTION WITH NUMONYX™ PRODUCTS. NO LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE, TO ANY INTELLECTUAL PROPERTY RIGHTS IS GRANTED BY THIS DOCUMENT. EXCEPT AS PROVIDED IN NUMONYX'S TERMS AND CONDITIONS OF SALE FOR SUCH PRODUCTS, NUMONYX ASSUMES NO LIABILITY WHATSOEVER, AND NUMONYX DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY, RELATING TO SALE AND/OR USE OF NUMONYX PRODUCTS INCLUDING LIABILITY OR WARRANTIES RELATING TO FITNESS FOR A PARTICULAR PURPOSE, MERCHANTABILITY, OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

Numonyx products are not intended for use in medical, life saving, life sustaining, critical control or safety systems, or in nuclear facility applications.

Numonyx may make changes to specifications and product descriptions at any time, without notice.

Numonyx, B.V. may have patents or pending patent applications, trademarks, copyrights, or other intellectual property rights that relate to the presented subject matter. The furnishing of documents and other materials and information does not provide any license, express or implied, by estoppel or otherwise, to any such patents, trademarks, copyrights, or other intellectual property rights.

Designers must not rely on the absence or characteristics of any features or instructions marked "reserved" or "undefined." Numonyx reserves these for future definition and shall have no responsibility whatsoever for conflicts or incompatibilities arising from future changes to them.

Contact your local Numonyx sales office or your distributor to obtain the latest specifications and before placing your product order.

Copies of documents which have an order number and are referenced in this document, or other Numonyx literature may be obtained by visiting Numonyx's website at http://www.numonyx.com.

Numonyx StrataFlash is a trademark or registered trademark of Numonyx or its subsidiaries in the United States and other countries.

*Other names and brands may be claimed as the property of others.

Copyright © 11/5/7, Numonyx B.V. All Rights Reserved.

M numonyx 66/66

